

Soft X-ray Spectromicroscopy on nanoscale

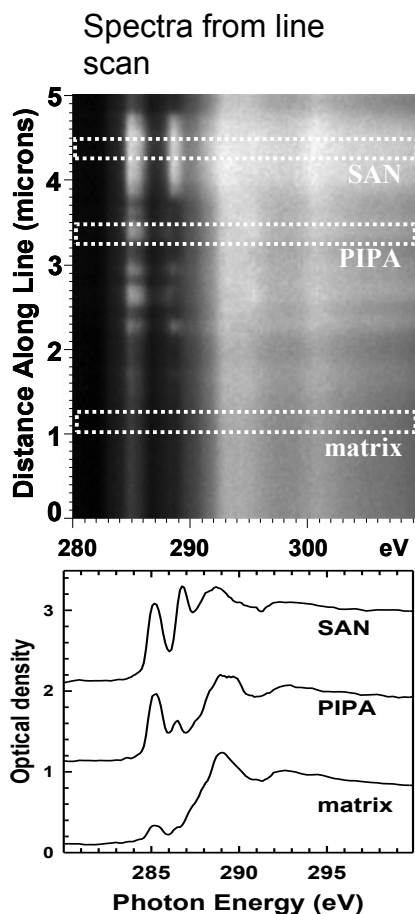
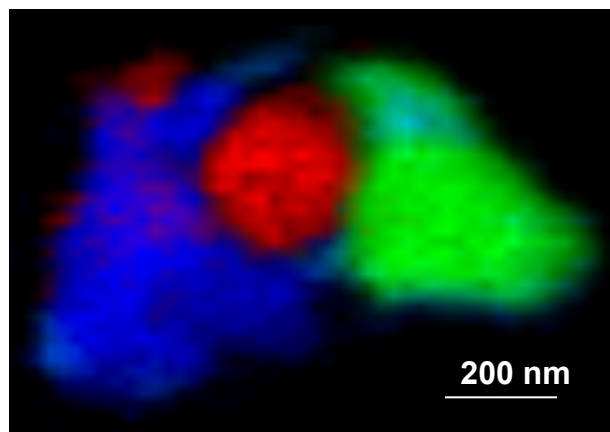
Tolek Tyliczszak
Advanced Light Source

Transmission X-ray Microscope – best tool for soft x-ray spectroscopy

$$I = I_0 e^{-\rho \mu d}$$

Can be measured at the same way as the I

MgaMgbMgc



Spectra from 150 individual images (stack analysis)

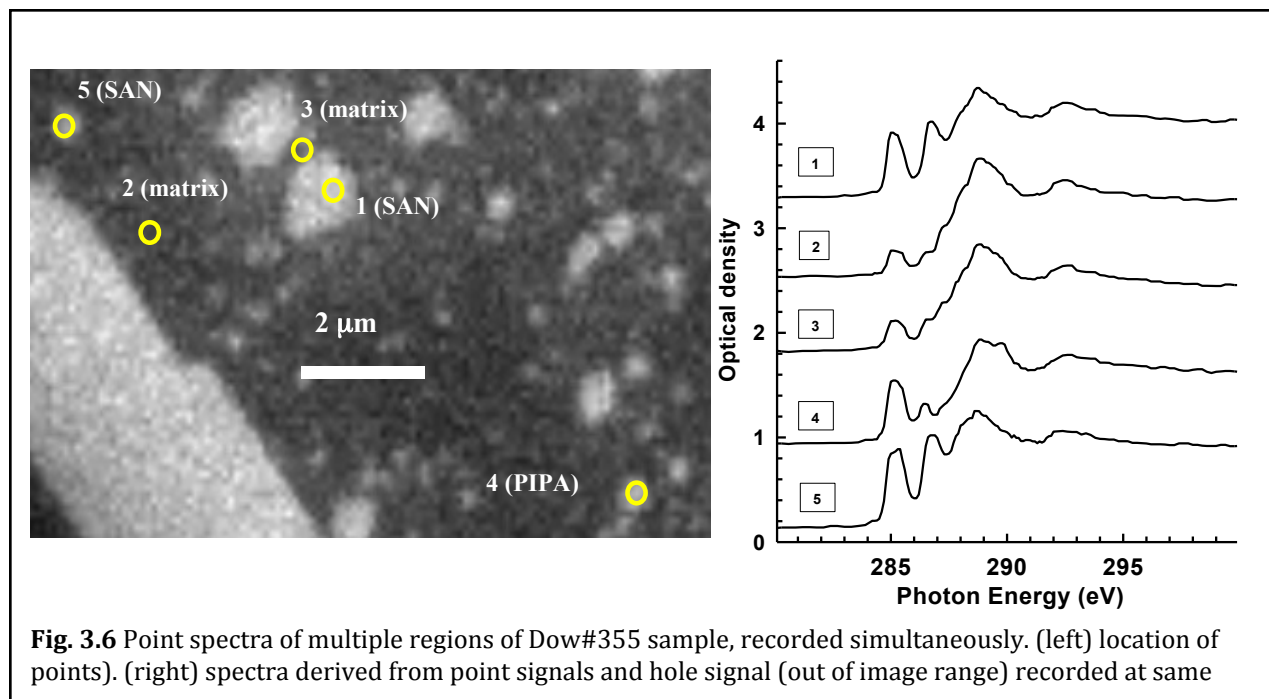
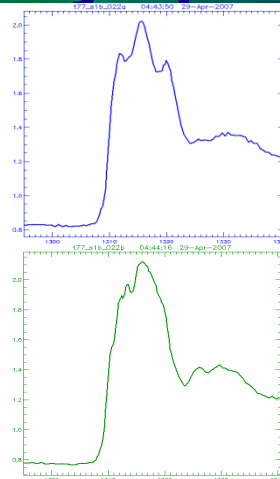
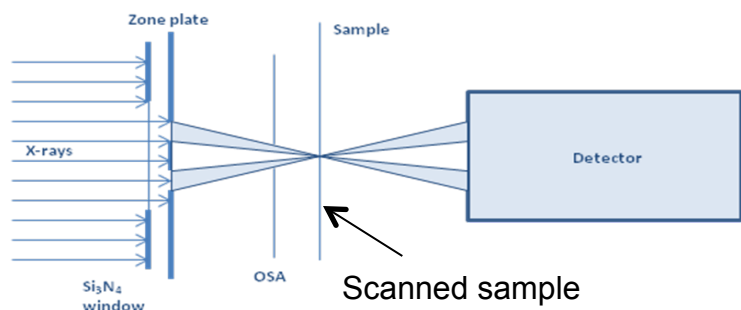
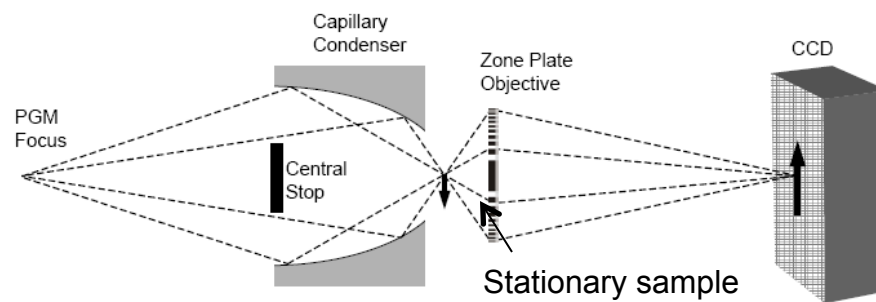


Fig. 3.6 Point spectra of multiple regions of Dow#355 sample, recorded simultaneously. (left) location of points). (right) spectra derived from point signals and hole signal (out of image range) recorded at same

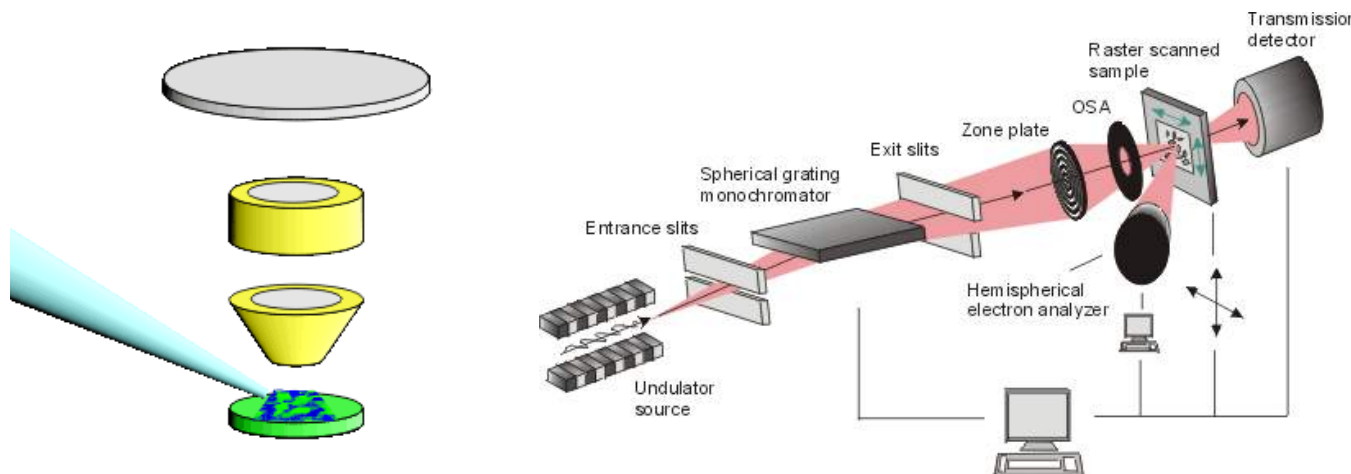
Soft X-ray Microscopy



Scanning Transmission X-ray Microscope (STXM)

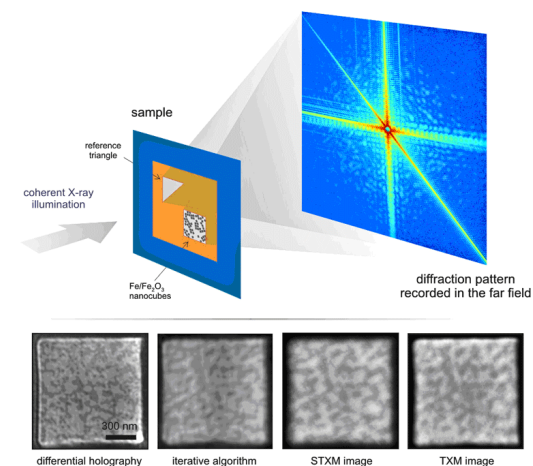


Transmission X-ray Microscope (TXM) - BESSY implementation

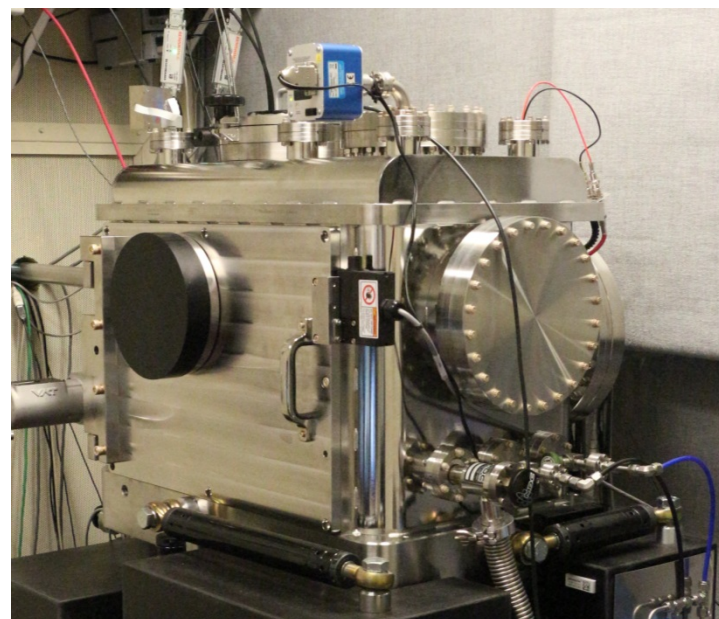
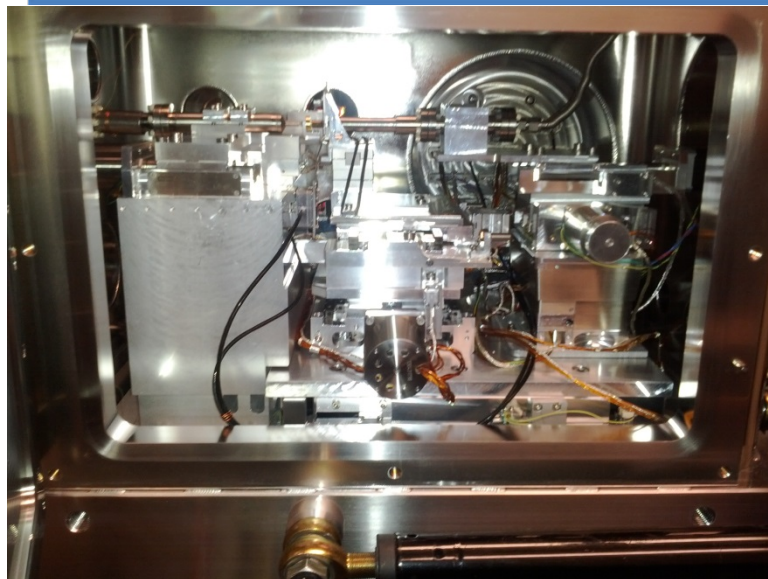
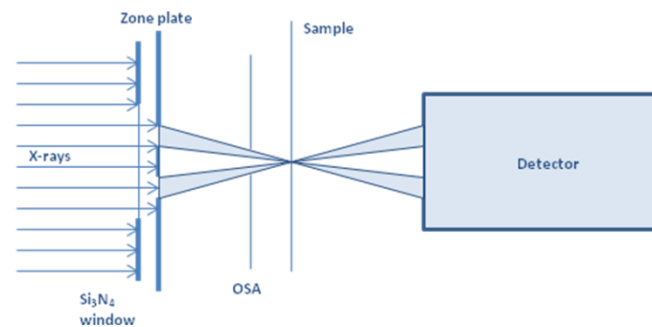
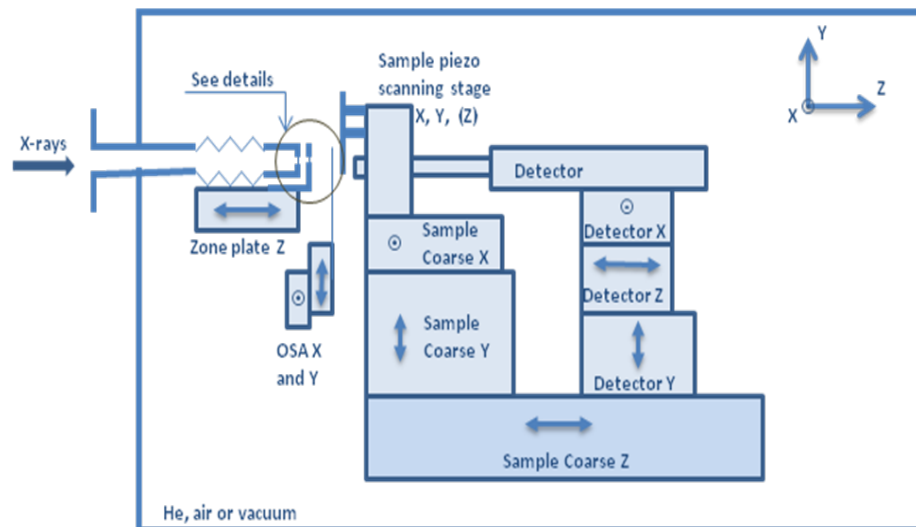


Photoelectron Emission Microscope (PEEM)

Scanning Photoemission Electron microscopy (SPEM)



Coherent Diffraction Imaging (CDI)



Soft X-ray Spectromicroscopy summary

Soft X-ray spectroscopy has high chemical sensitivity
Combined with a microscope provide high chemical sensitivity on nanoscale

Current x-ray microscope spatial resolution:

- 10 nm for imaging

- 50 nm for spectroscopy

Ways to improve resolution:

- Ptychography (combination of transmission scanning microscope with diffraction) - very promising

- Improvement of the zone plates - technical limitation

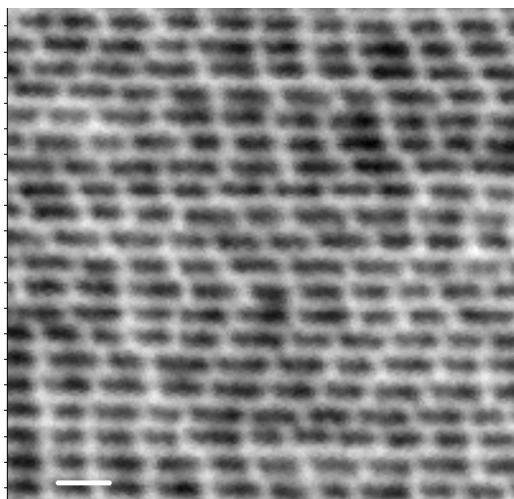
- Laue lenses - difficult to make for soft X-rays

- Combination of the scanning transmission microscope and scanning probe microscope for modification of the X-ray beam shape -

- PEEM - demonstrated 5nm at VUV, for x-rays needs better aberration correction, energy filters

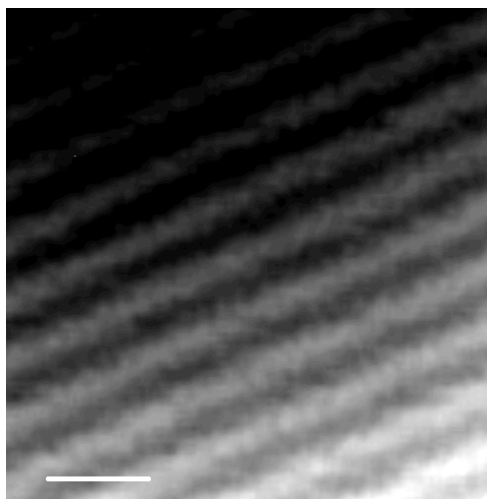
Zone plates and achieved resolution

25 nm zone plate



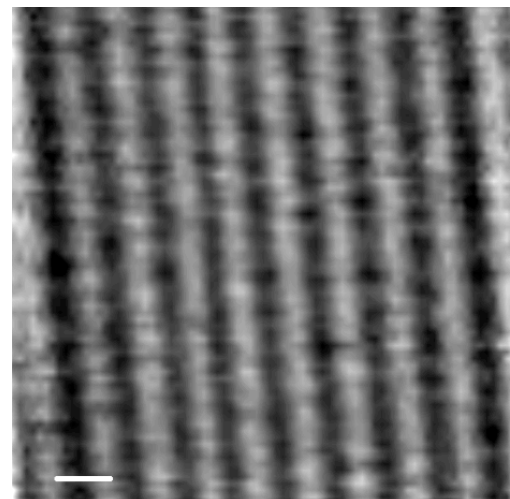
20 nm (vertical) Au lines

20 nm zone plate



12 nm lines Si/Mo

17 nm zone plate



10 nm lines Si/Mo



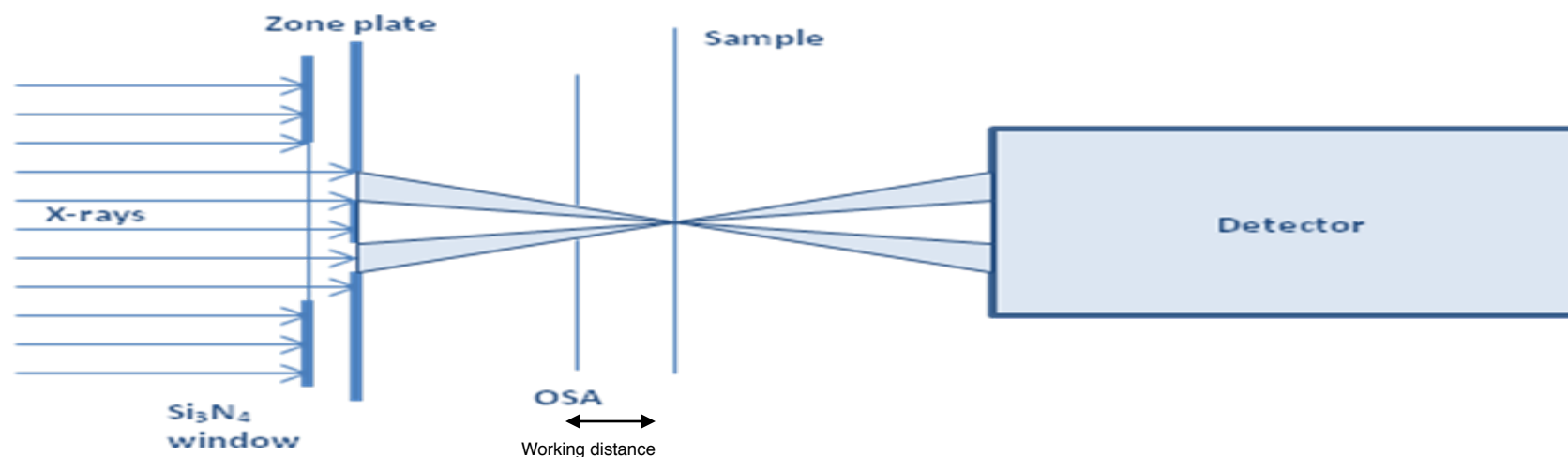
9 nm lines Si/Mo
Imaged by 17 nm zone plate

All images taken at 700 eV

Structures have equal line/space nominal dimensions
Dimensions of half periods are quoted

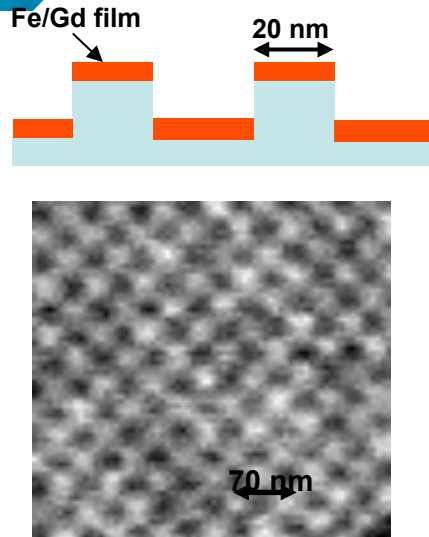
Zone plates and working distance

$$\text{Beam size } d = 1.22 * \Delta R$$

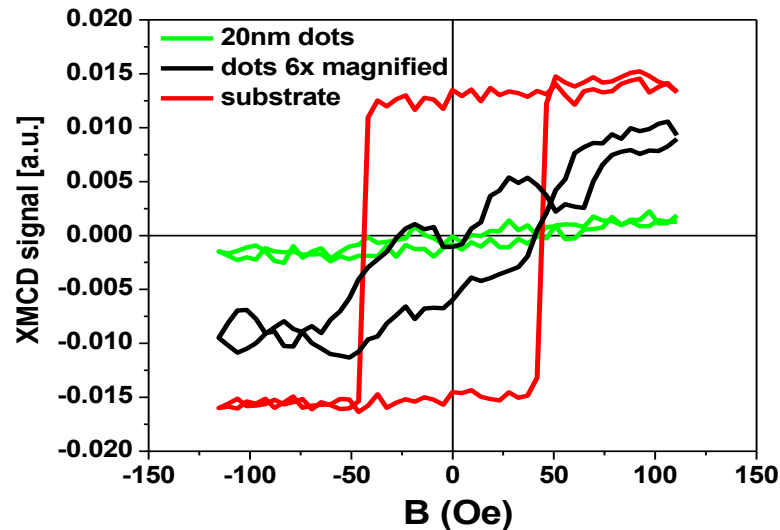


ΔR [nm]	D [μm]	Working distance	Focal length [mm]		
		at 300 eV	300 eV	700 eV	1800 eV
45	240	700	2810	6790	17460
25	240	350	1467	3423	8802

spectroscopy – XMCD - magnetism



STXM image of EUV structured Fe/Gd dots with a diameter of 20 nm and a periodicity of 70 nm recorded at the Fe L_3 edge



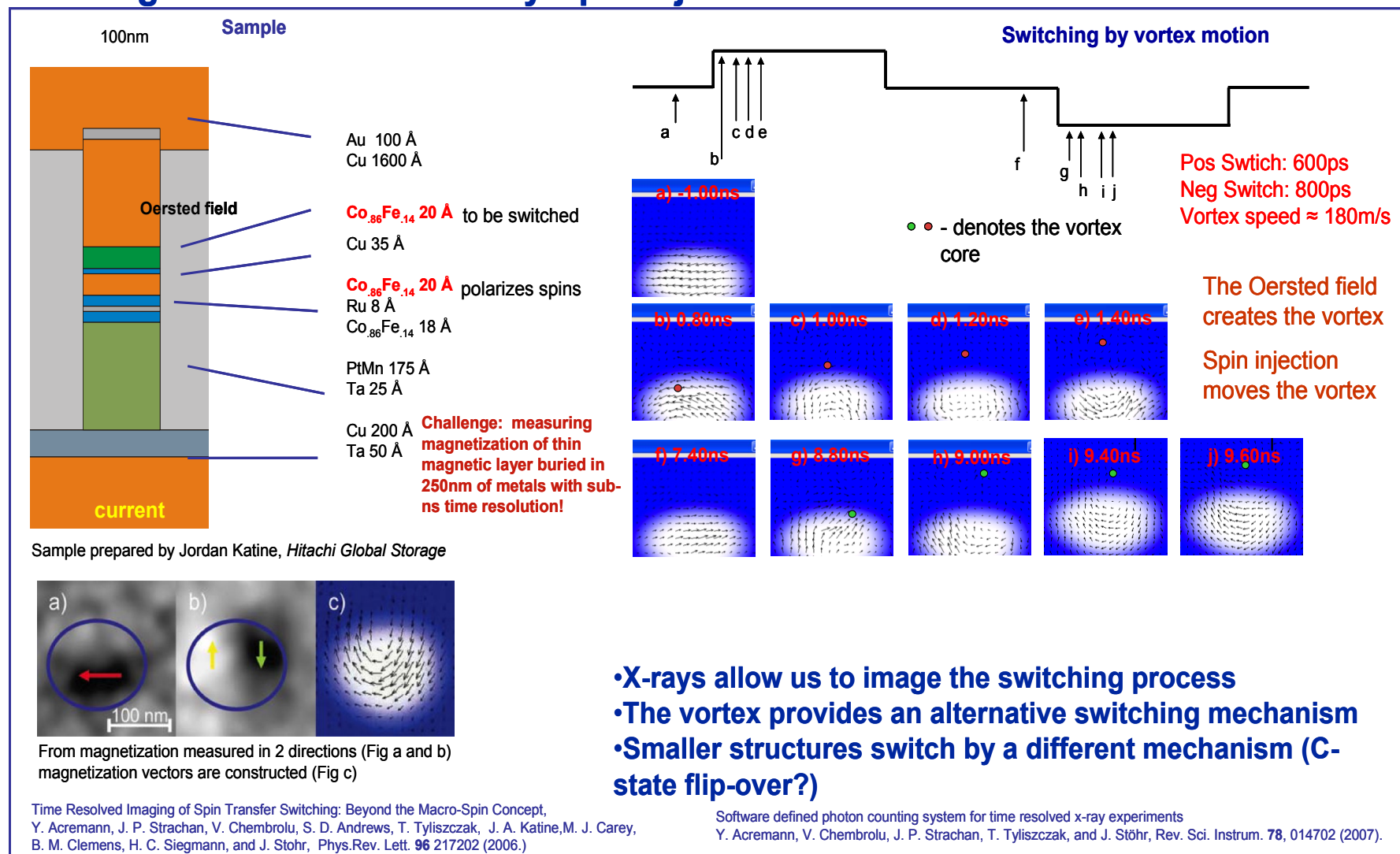
Hysteresis loop of 20 nm dots (ensemble) and of the film between the dots measured by XMCD

Nanopattern magnetic structure – investigations of magnetization of technologically important behavior in external magnetic/electric field

T. Eimüller, E. Amaladass, F. Luo, T. Tyliczszak,

Direct observation of magnetization reversal by spin injection – ultimate X-ray microscope challenge

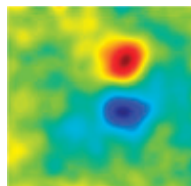
Magnetization Reversal by Spin Injection



Measurements of magnetization distribution dynamics of 2 nm layer buried in 200 nm metal of 100 nm diameter pillar with 70 ps resolution

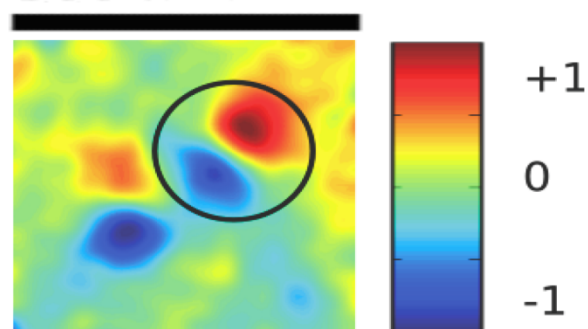
X-ray imaging of the dynamic magnetic vortex core deformation

Exp. 160 m/s



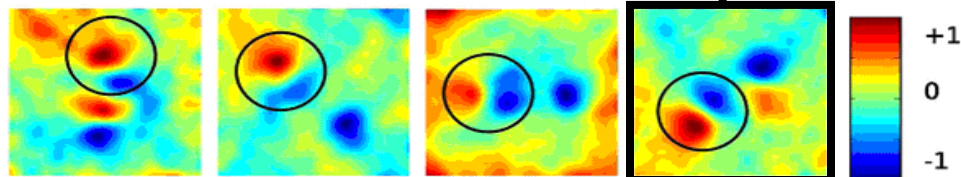
Vortex core size 10-20 nm

300 nm



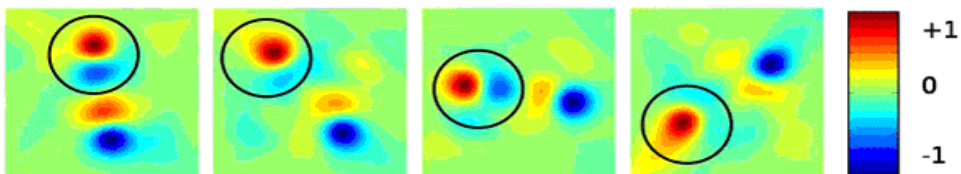
(b) exp. 260m/s

300 nm

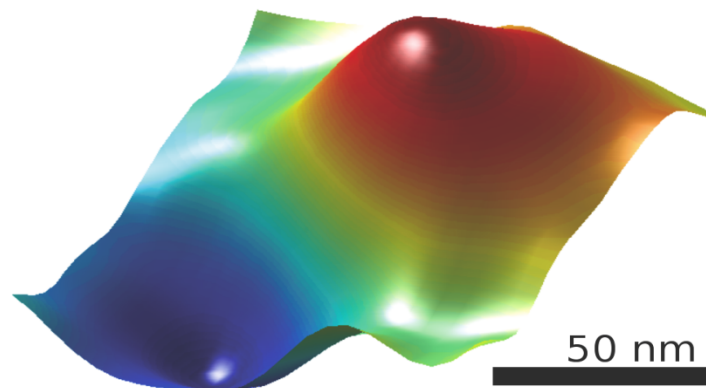


(d) sim. (differential, convoluted)

differential intensity



0 222 444 666
time (ps)

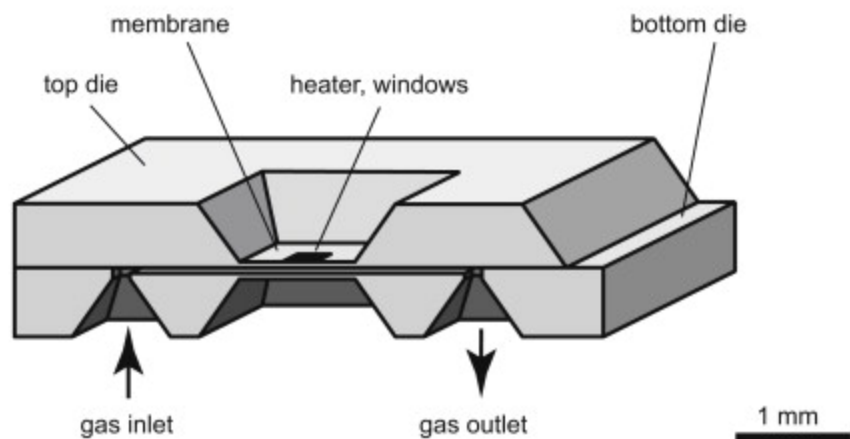


A. Vansteenkiste, K.W. Chou, M. Weigand, M. Curcic, V. Sackmann, H. Stoll, T. Tyliszczak, G. Woltersdorf, C. H. Back, G. Schütz and B. VanWaeyenberge, Nature Physics, 2009

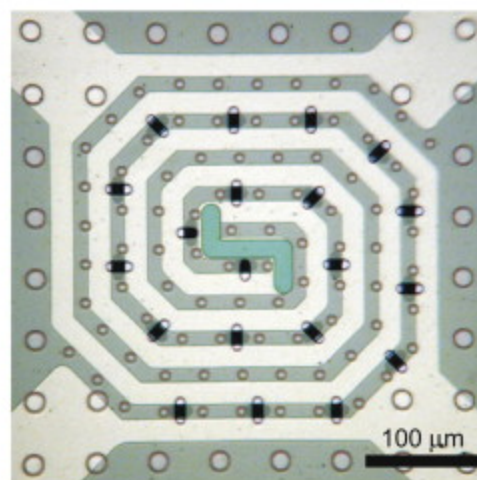
In-Situ STXM environmental cell #2

450°C, 2 bar

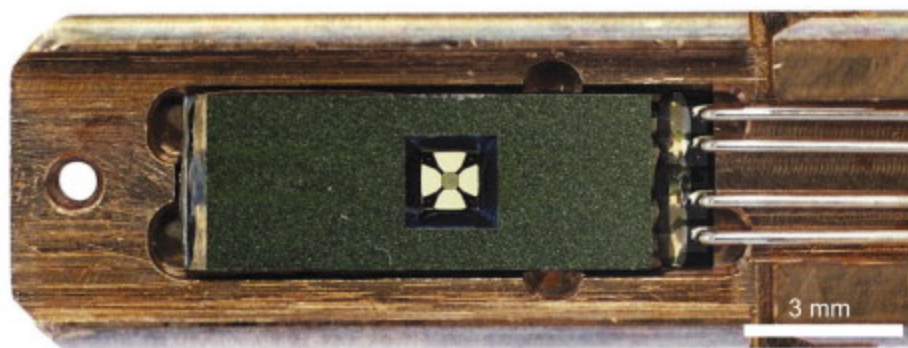
a



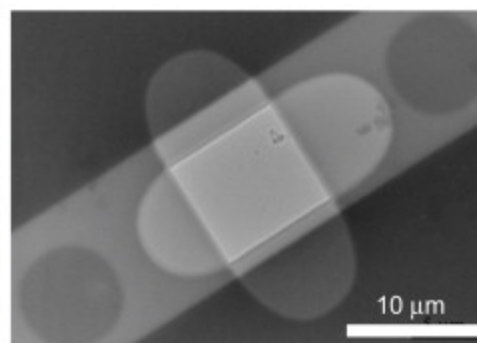
c



b



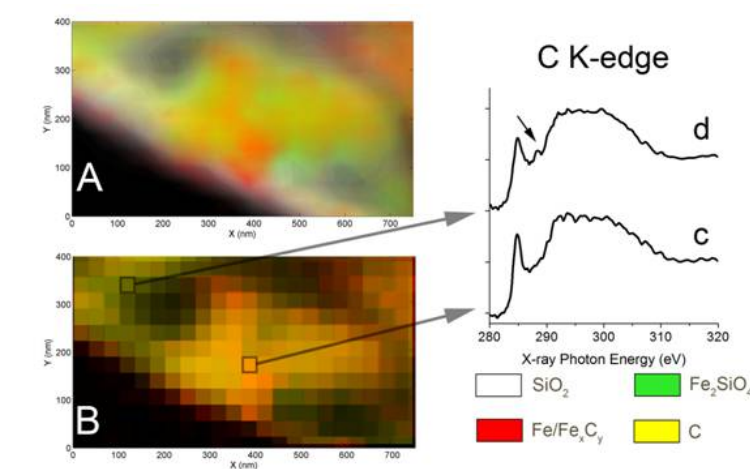
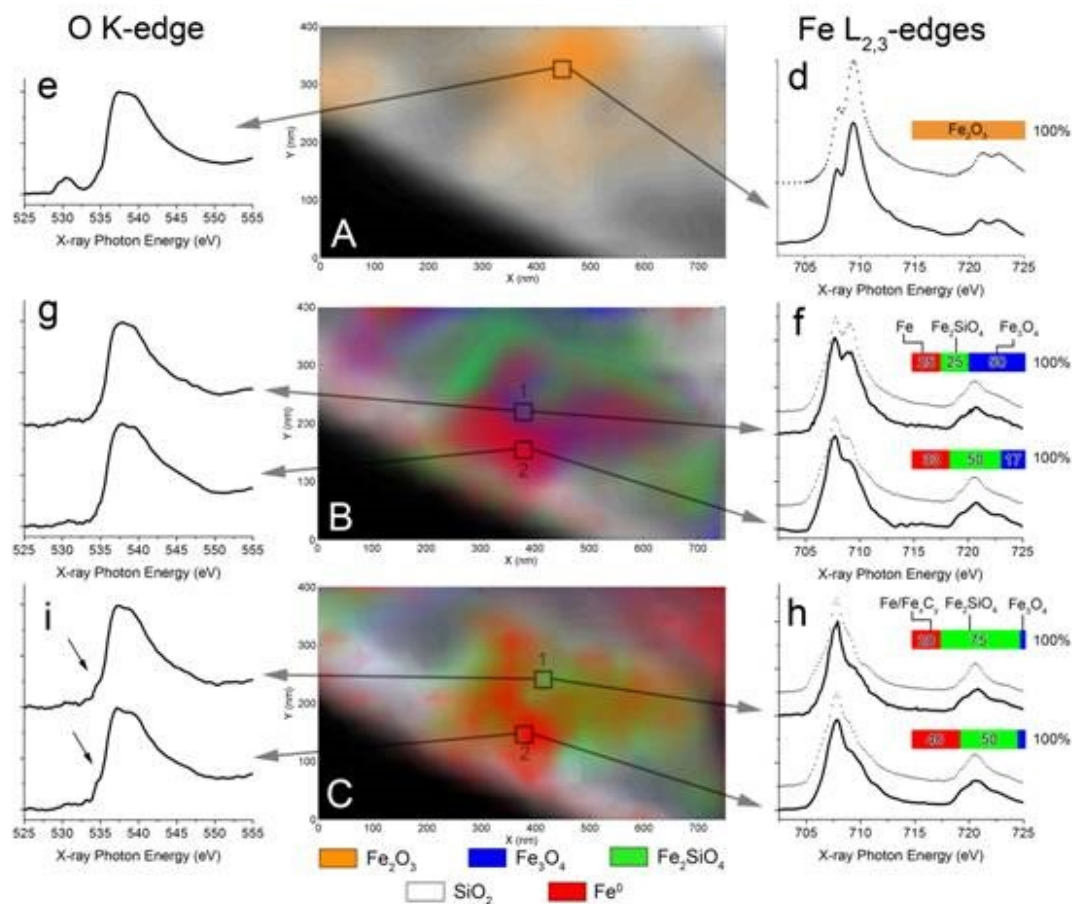
d



Creemer, J. F. et al., Ultramicroscopy 108, 993–998

In situ catalytic reactions

complex iron oxide based Fischer-Tropsch catalyst

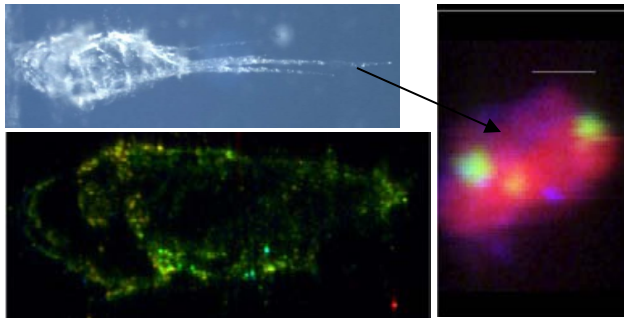


:Chemical contour maps of a region of a catalyst particle during the different stages of reaction. A: Before treatment at RT in 1 bar He. B: After 2h in H₂ at 350°C. C: After 4h in CO/H₂ at 250°C. The corresponding regions of the O K-edge (e, g, i) and Fe L_{2,3}-edge spectra (d, f, h) are indicated in the figures. Dotted lines indicate the linear combination fits, with the bars representing the contribution of the different phases to the spectra.

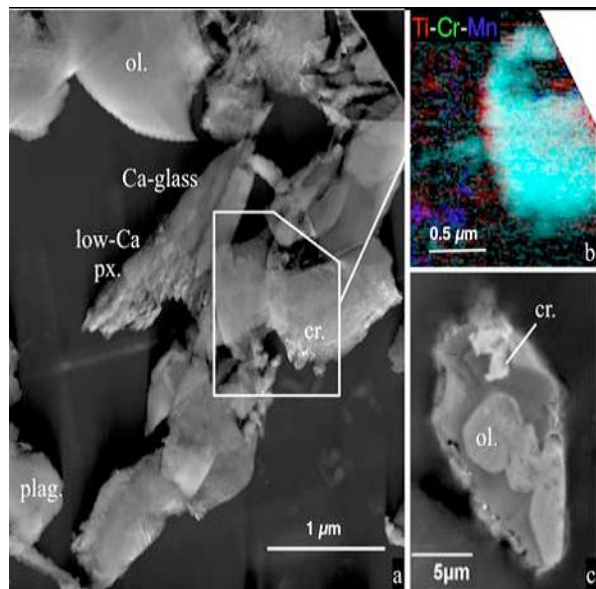
E. de Smit, I. Swart, J. Creemer, G. H. Hoveling, M. K. Gilles, T. Tyliszczak, P. J. Kooyman, H. W. Zandbergen, C. Morin, B. M. Weckhuysen and F. M. F. de Groot, *Nature* **456**, 222 (2008).

Cometary Particles

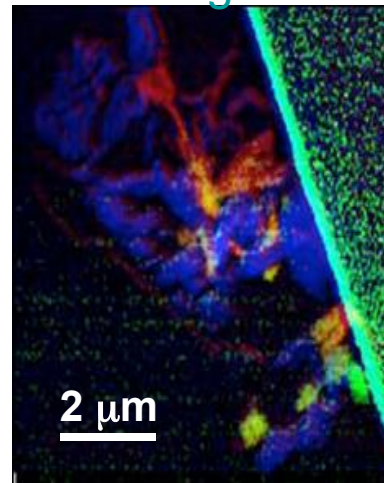
TYPE IIA CHONDRULE FRAGMENT FROM COMET 81P/WILD2 IN STARDUST TRACK C2052,2,74



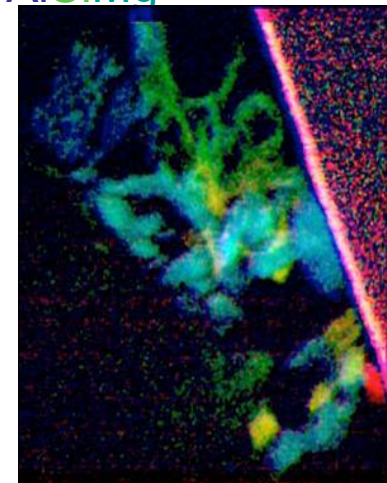
Optical and X-ray Fluorescence images



CaAlMg



AlSiMg

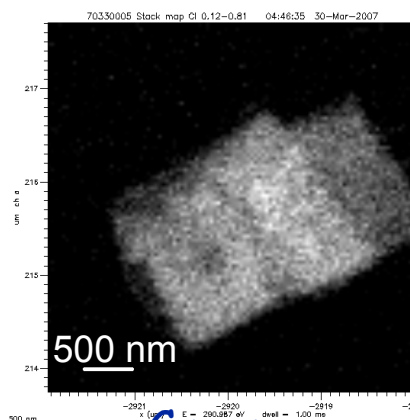
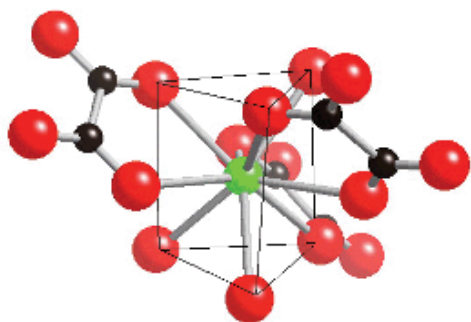


STXM element maps of Iris,9. Absorption difference maps, pixel size 100 nm. a) Ca-Al-Mg-. Yellow regions are Ca-Al rich, Purple regions are Ca-bearing Mg-Fe silicates. b) Al-Si-Mg map, the minerals are labeled as for Fig. 3.

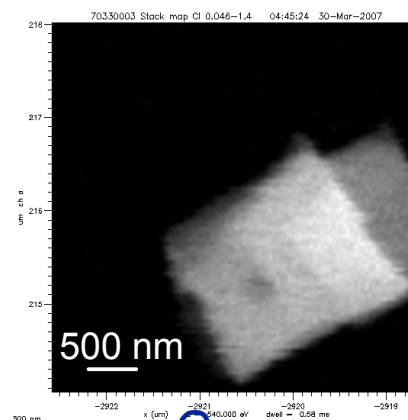
STXM provided detail understanding of chemical composition before the TEM work to identify crystalline structure

A. L. Butterworth Z. Gainsforth, A. Bauville, L. Bonal, D. E. Brownlee, S. C. Fakra, G. R. Huss, D. Joswiak, M. Kunz, M. A. Marcus, K. Nagashima, R. C. Ogliore, N. Tamura, M. Telus, T. Tyliczszak, A. J. Westphal

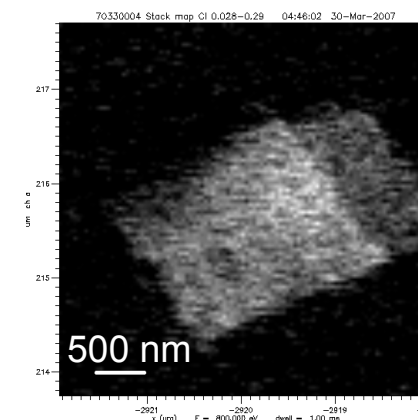
Pu(III) Oxalate $\left[\text{O}=\text{C}-\text{C}=\text{O} \right]^{2-}$



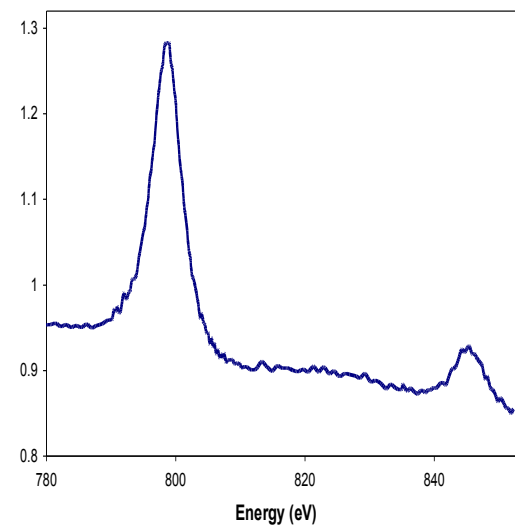
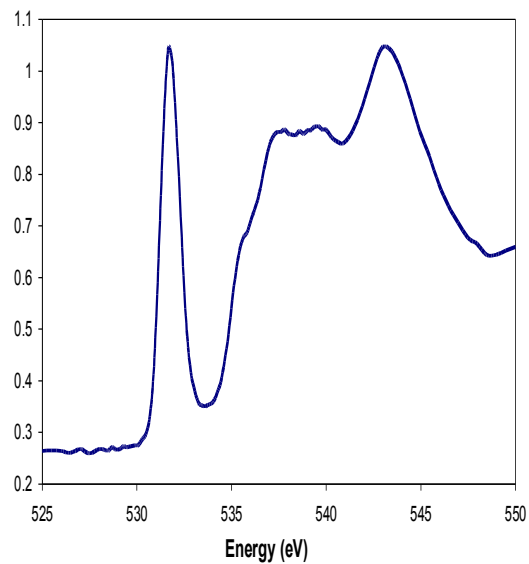
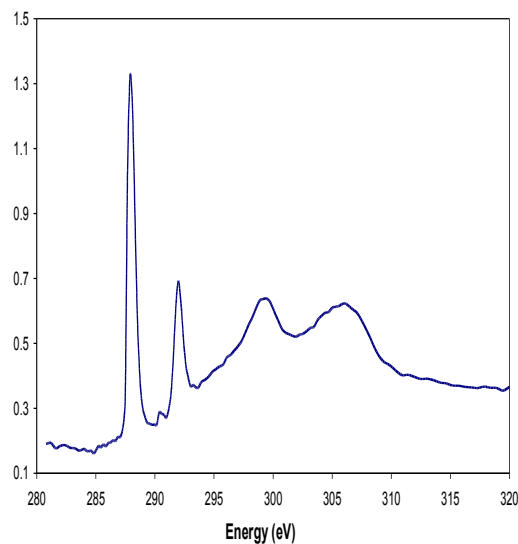
C map



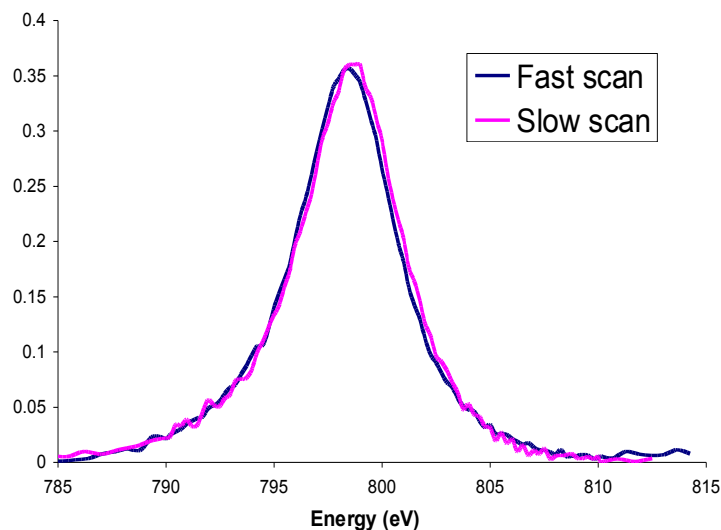
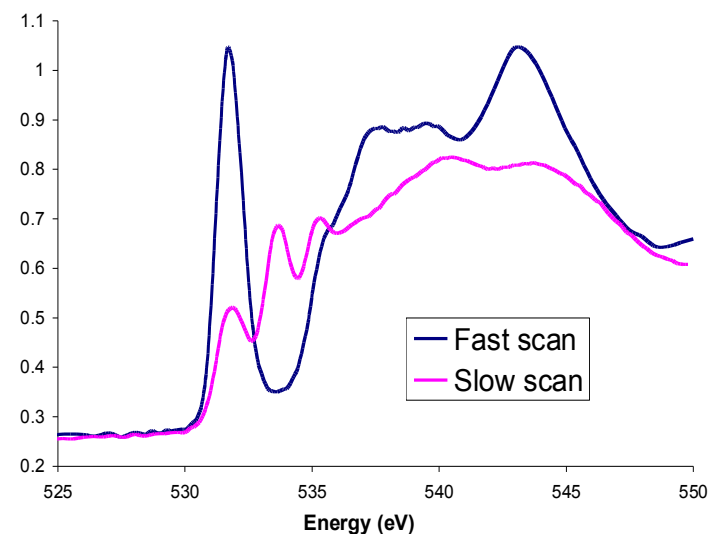
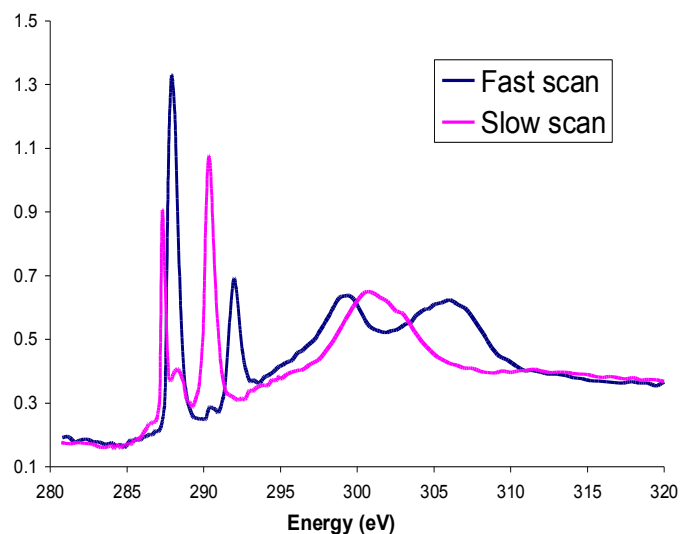
O map



Pu map



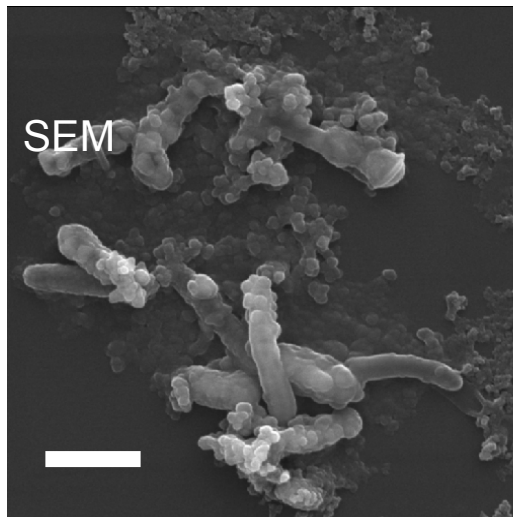
Pu(III) Oxalate Radiation Damage



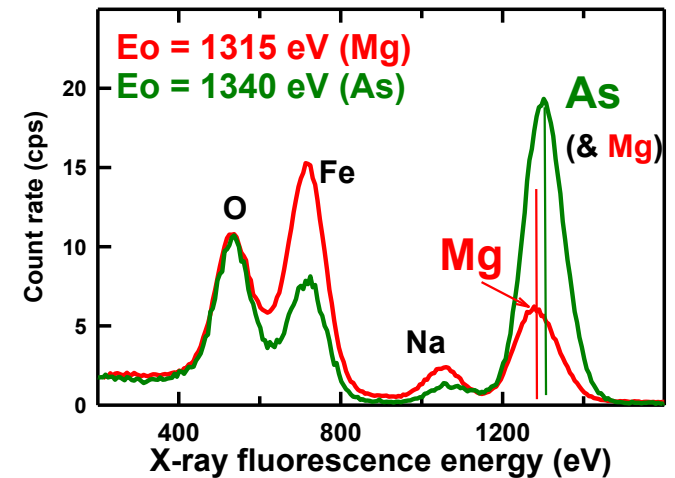
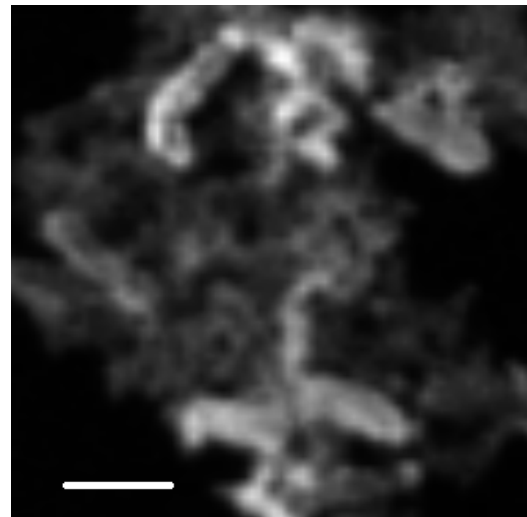
Fast scan – 100 μ s/pixel + reduced flux + fewer points
Slow scan - 1 ms/pixel

X-ray fluorescence in STXM

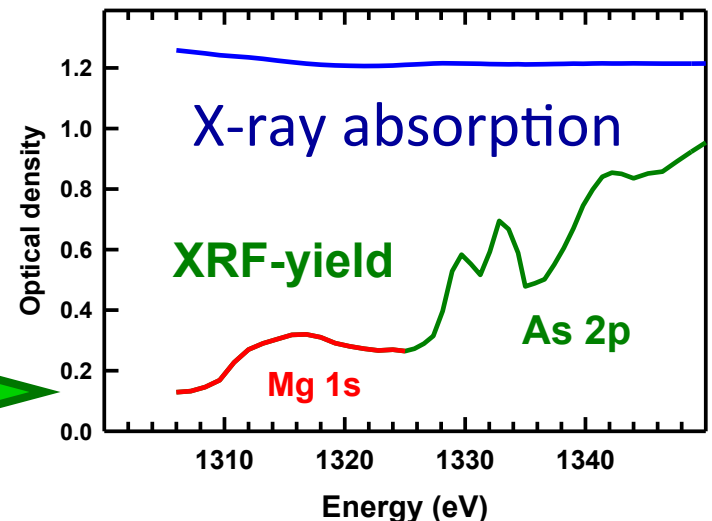
Adam Hitchcock (McMaster), Martin Obst (Tuebingen), Tolek Tyliczszak (ALS)



As map



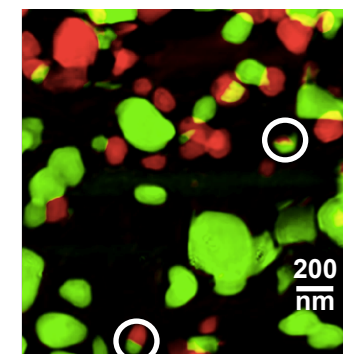
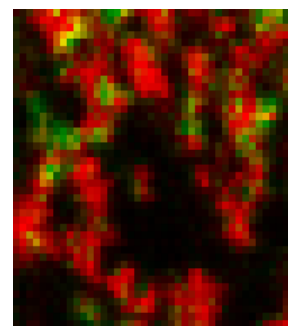
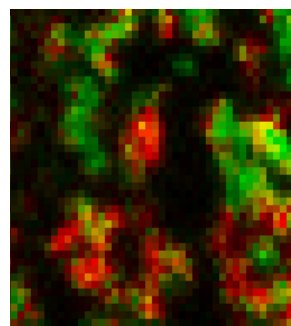
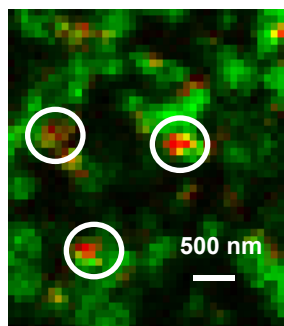
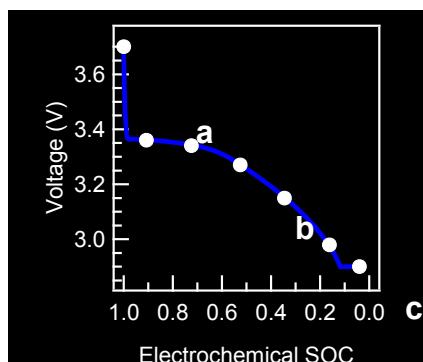
X-ray fluorescence yield X-ray absorption provides a reliable **As map** and **spectra** in a case where the conventional **transmission signal** does not detect it.



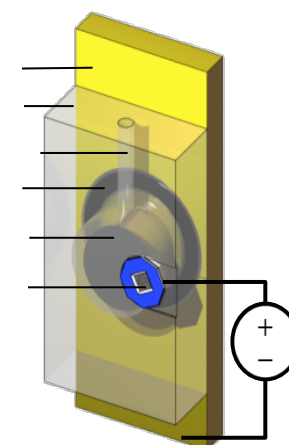
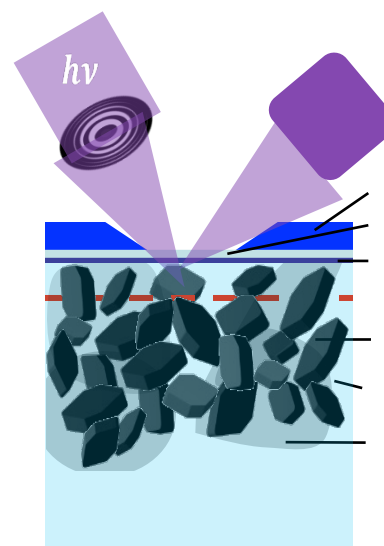
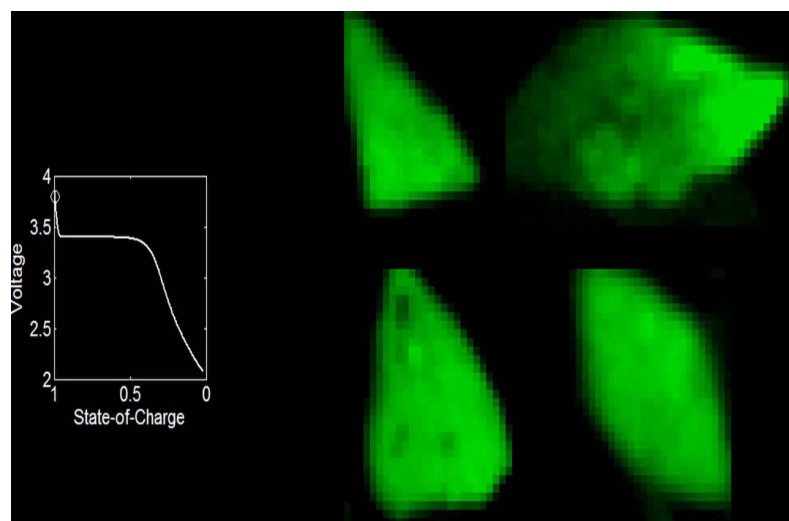
Lake Constance Acidovoris biofilm (BoFeN) cultured on 10 mM Fe(II). & 1 mM As

RELEVANCE: species is very tolerant to high As levels - WHY ?

Tracking Lithiation in Real Time in Liquid



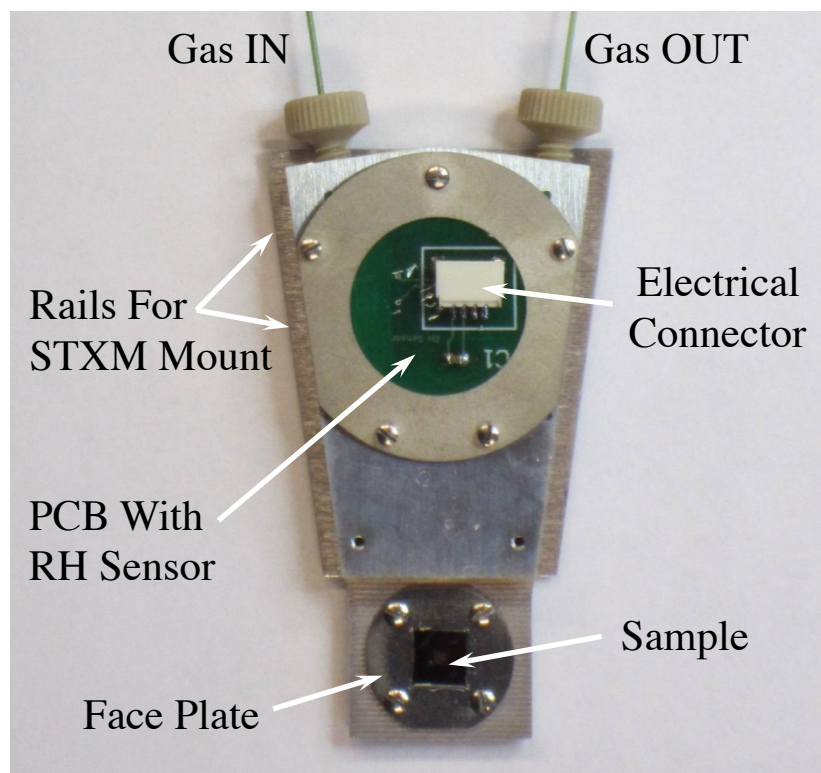
Particle-by-particle intercalation pathway



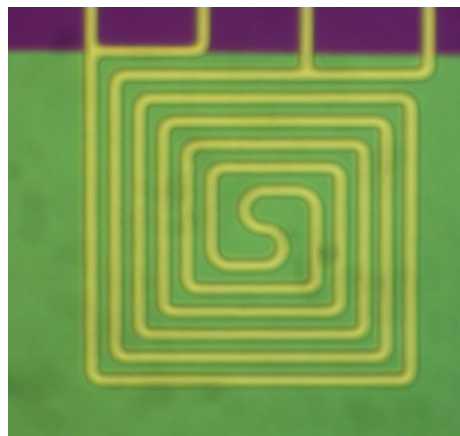
SOC



Gas flow nonoreactor



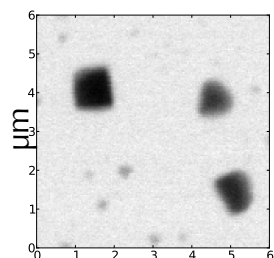
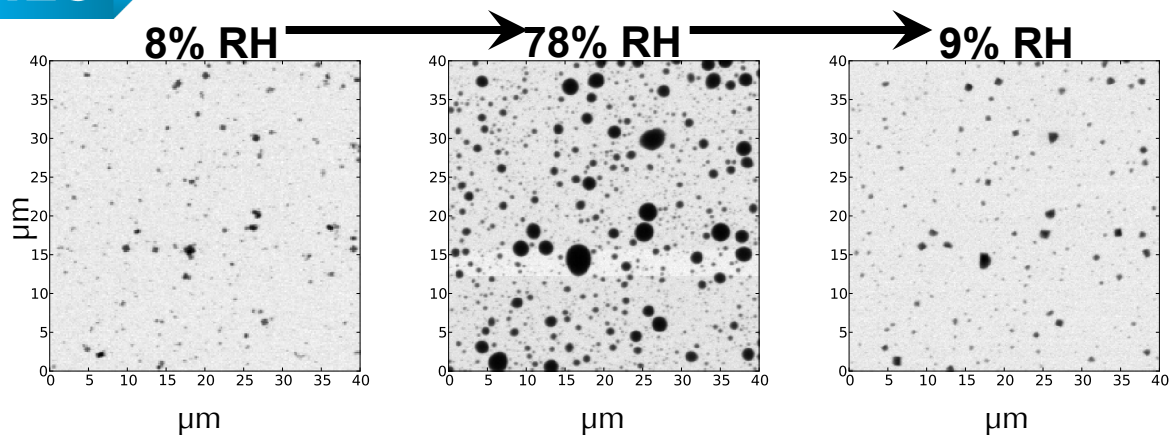
- Measurements under realistic conditions
 - CO_2 , H_2O , etc.
- *In situ* observation of chemical changes
- Mounts to existing STXM sample holder
- Real-time on-board measurement of relative humidity



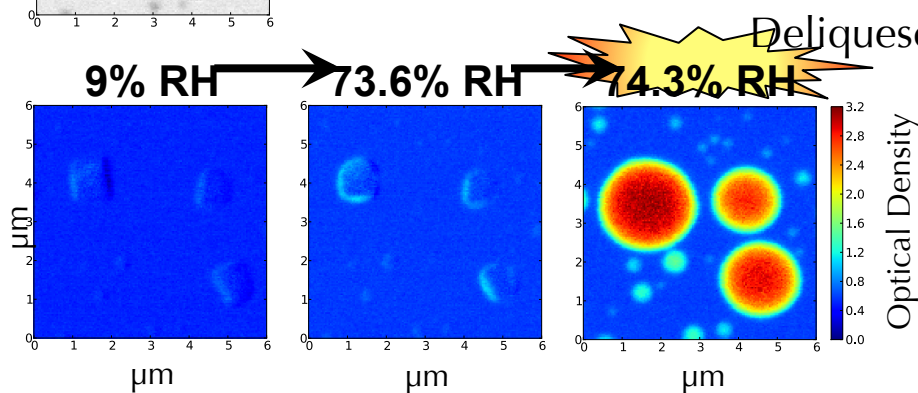
- Gold and platinum coils
- Four contacts:
 - 2 x Voltage (measure)
 - 2 x Current (supply)
- Resistively heats Si_3N_4 sample area
- Coil resistance gives average temperature measurement

Stephen T. Kelly, Gregory T. Carroll, Tobias Roedel, Pascal Nigge, Shruti Prakash, Alexander Laskin and **Mary K. Gilles**

Relative Humidity test

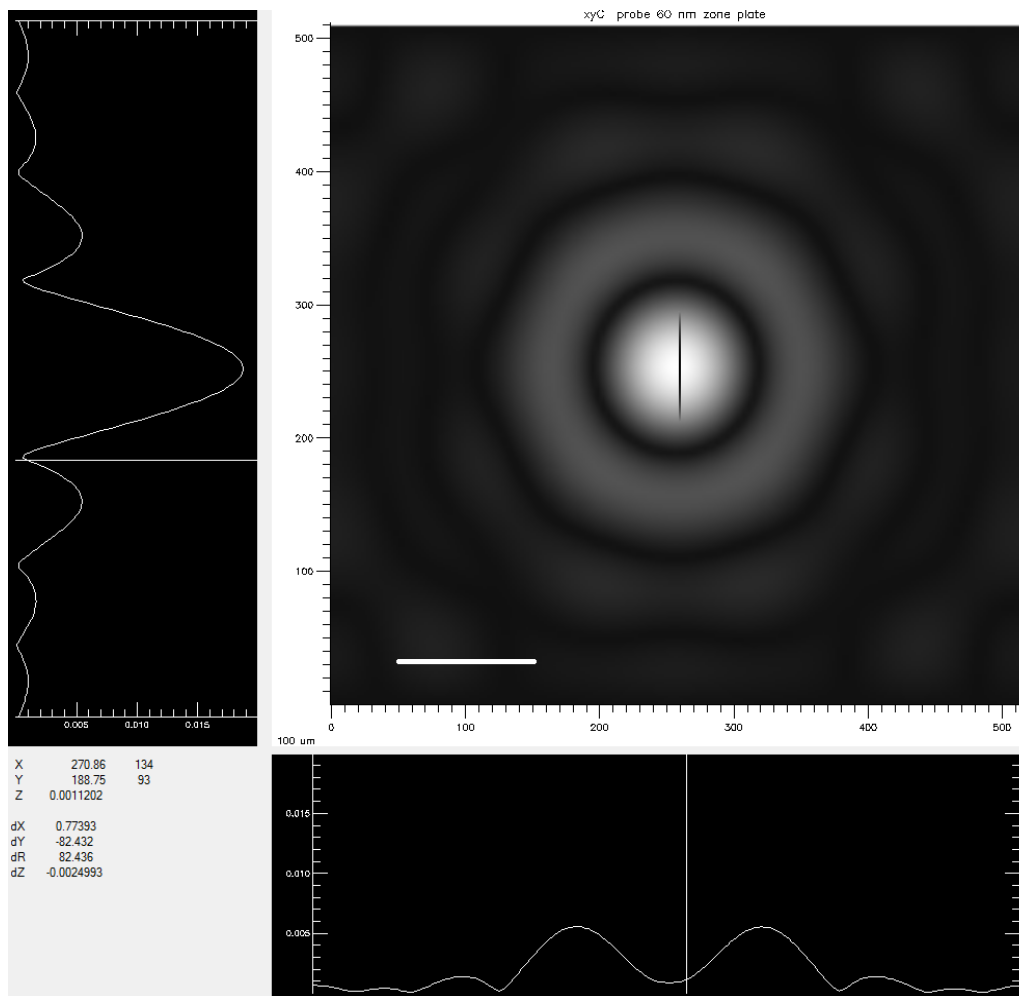


NaCl Deliquescence Relative Humidity – 75%

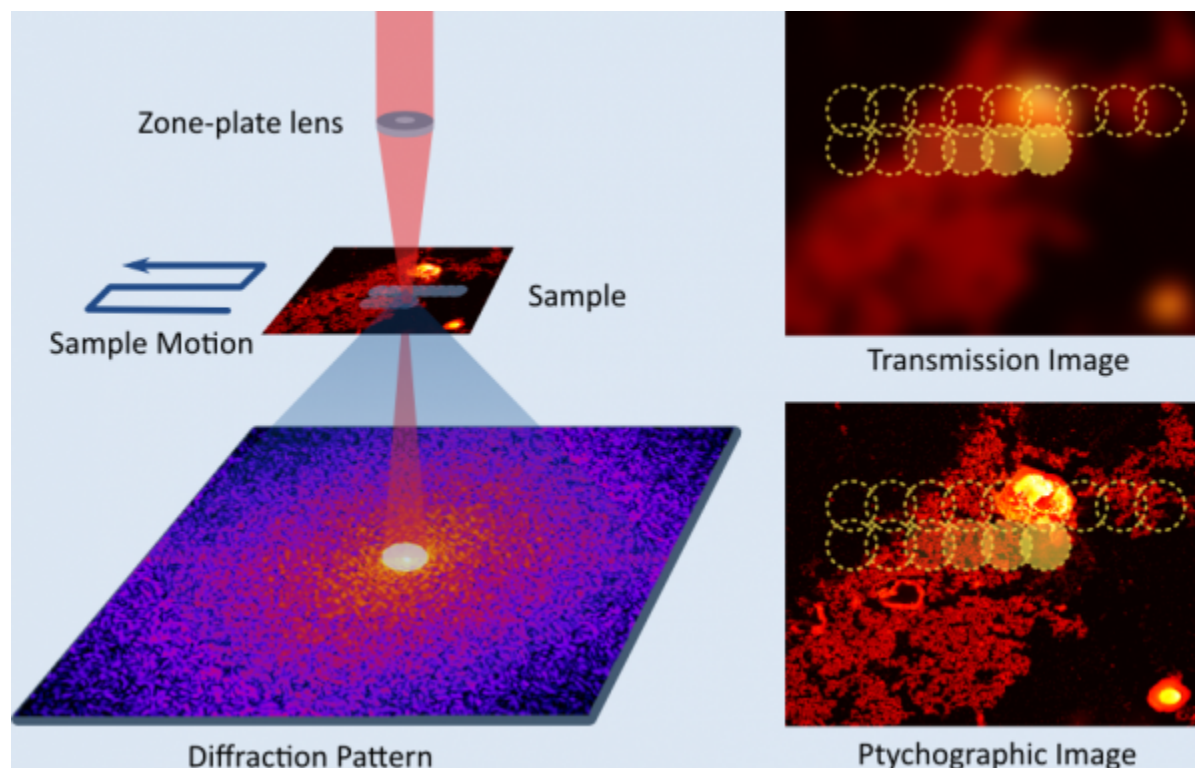


Mary Gilles group has also liquid flow cell

Beam profile and its consequences

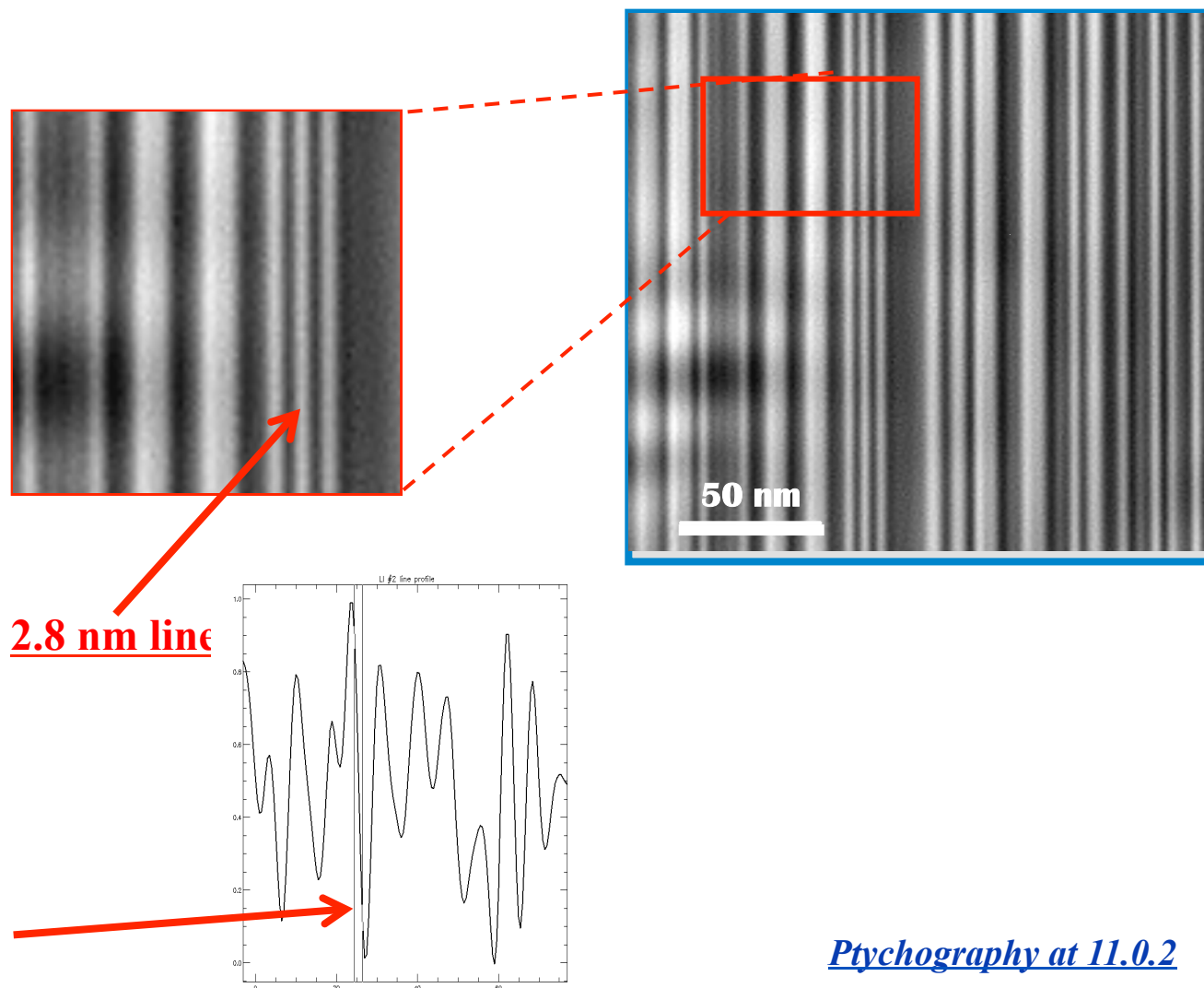


Ptychography



Sample is scanned in the plane of focused, coherent X-ray beam with steps smaller than the beam size. At each step, a diffraction pattern is recorded. Amplitude and phase shift images of the sample are reconstructed with much higher resolution than the beam size.

The Best Spatial Resolution of Soft X-ray Microscopy < 2 nm resolution

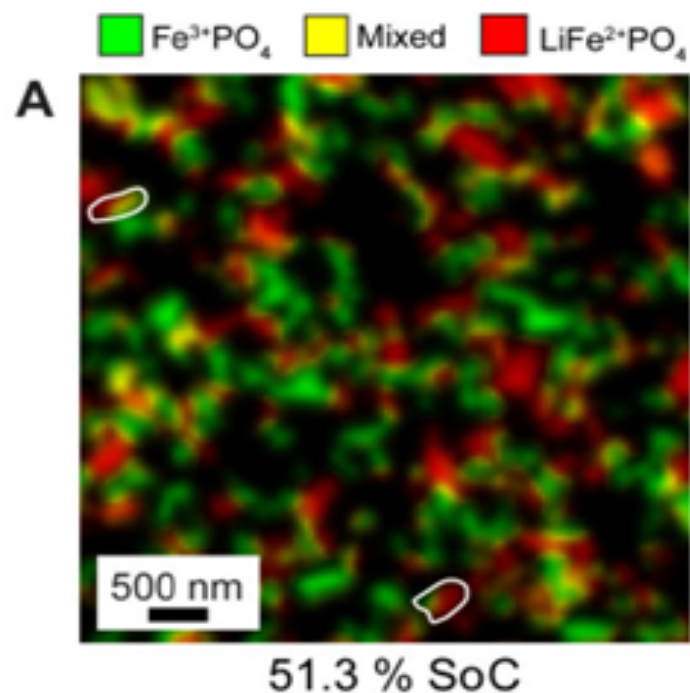


Ptychography at 11.0.2

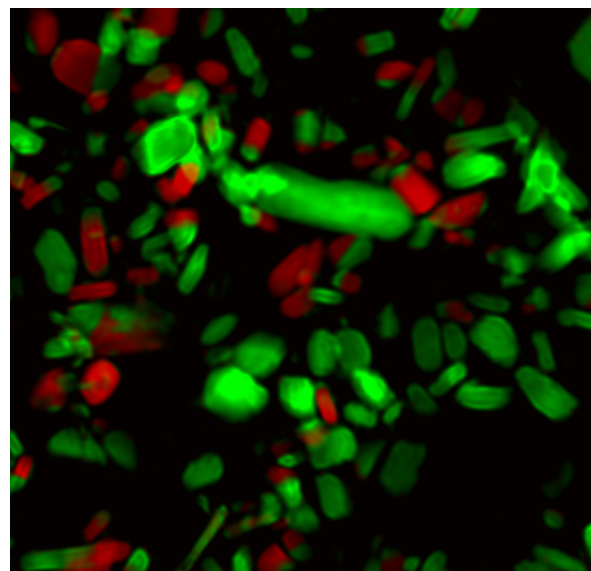
Ptychography

Ptychography – 6 nm resolution for chemical mapping

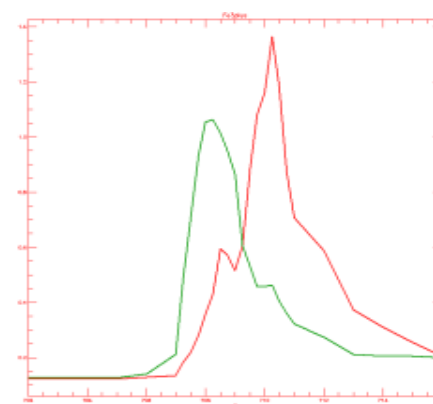
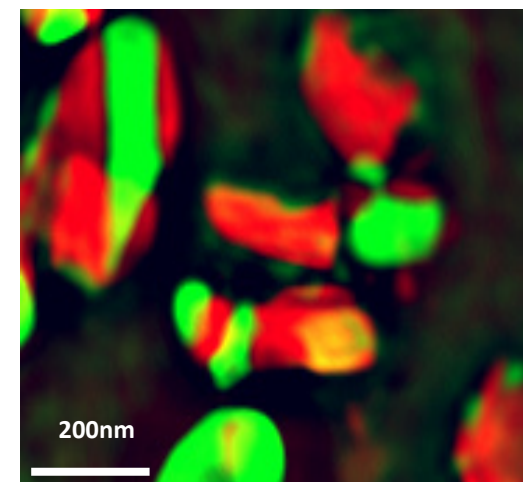
State-of-Charging Mapping via STXM

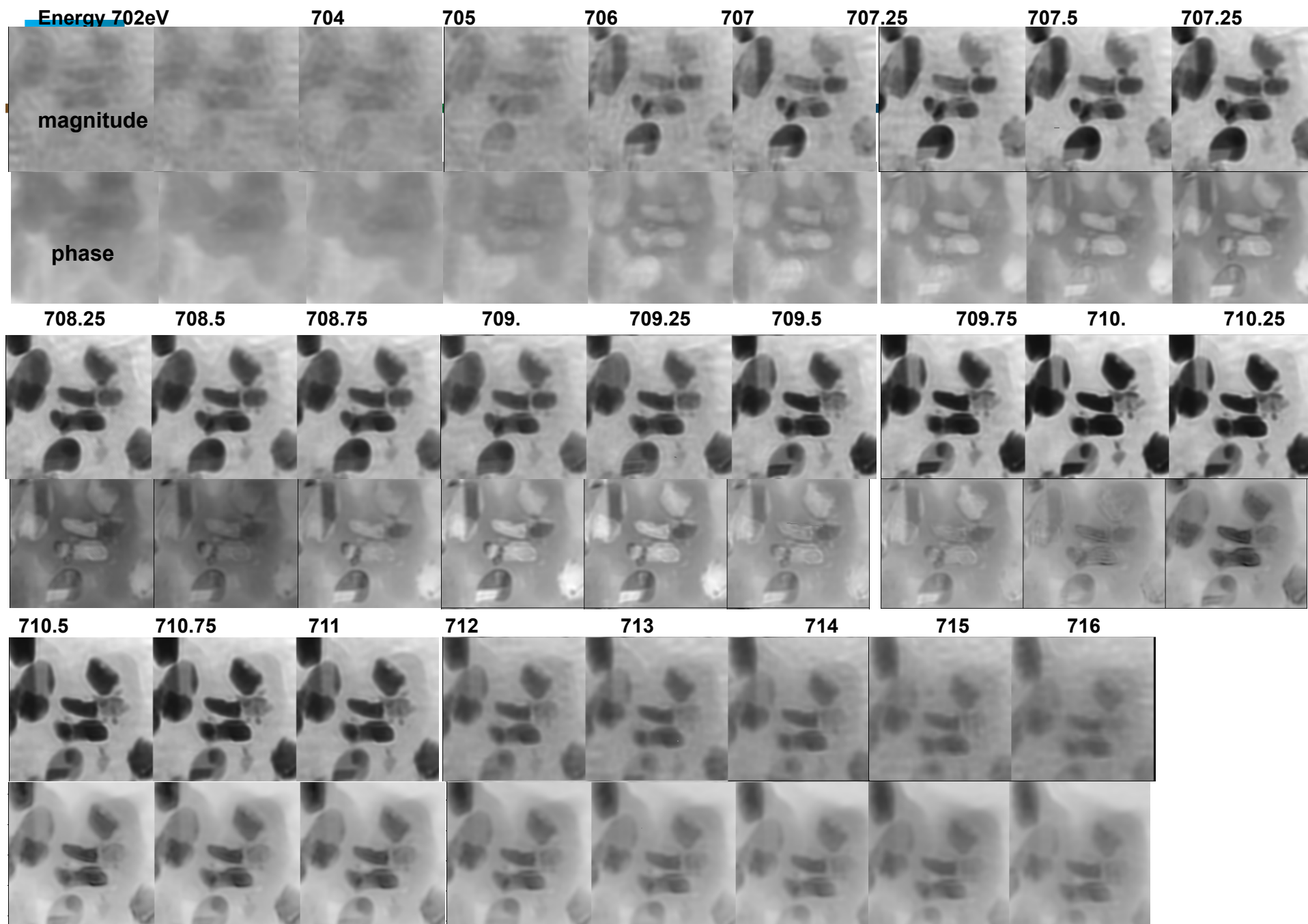


Chemical mapping from 3 energy

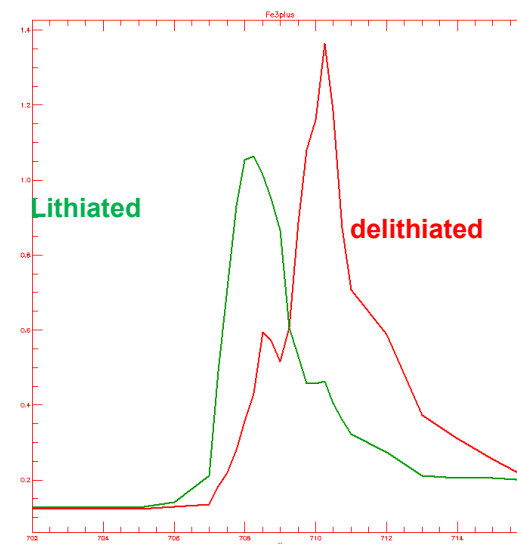
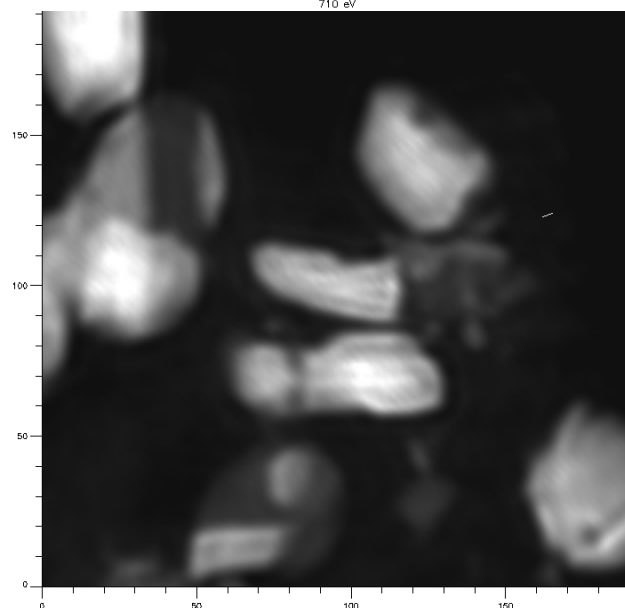
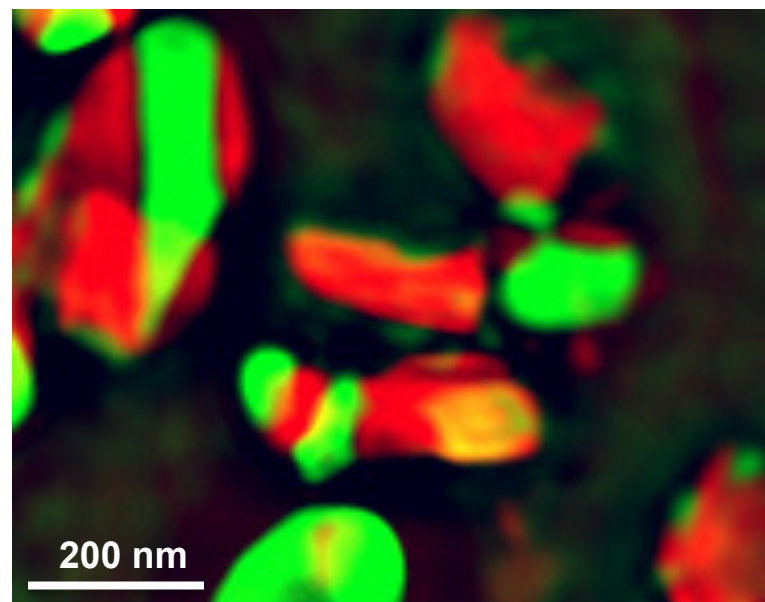
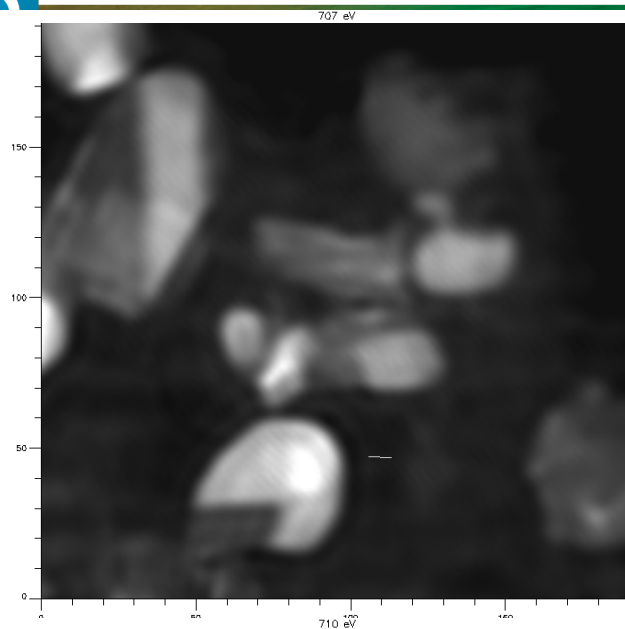


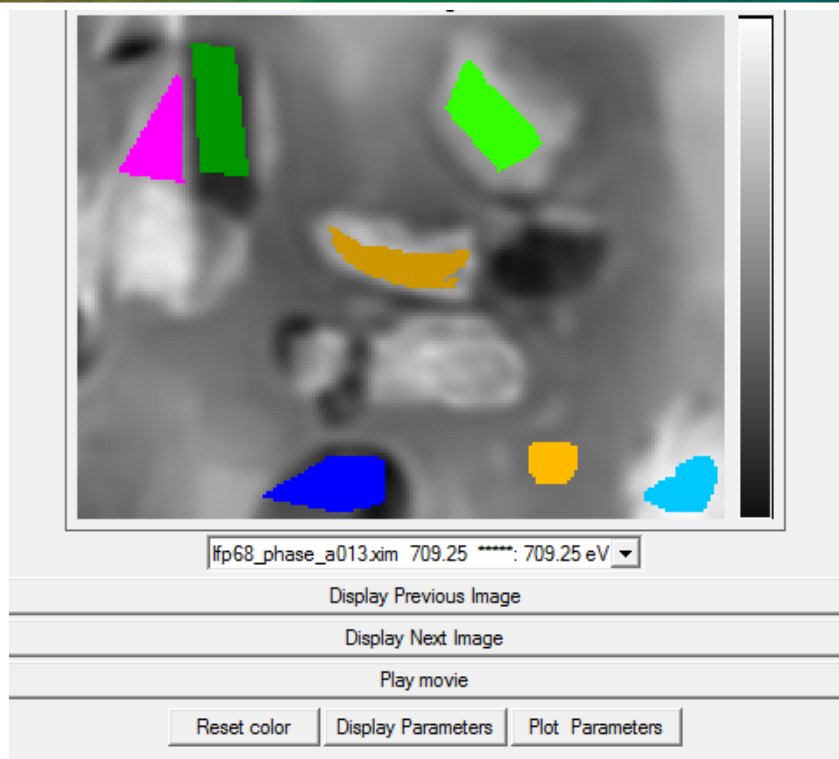
Chemical mapping from a stack



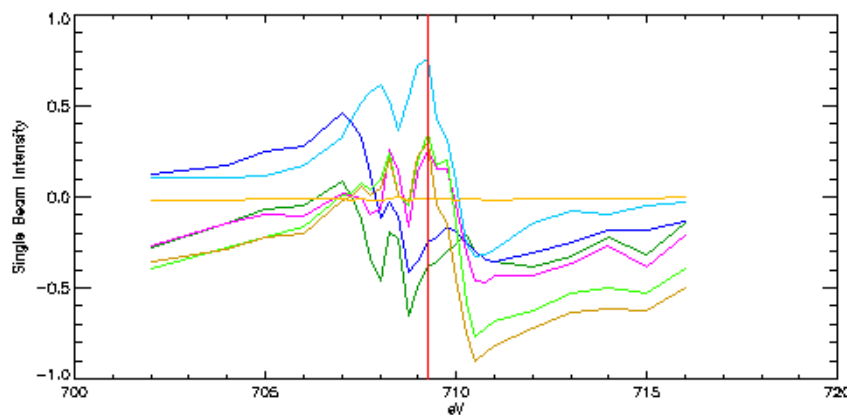


Ptychography spectromicroscopy

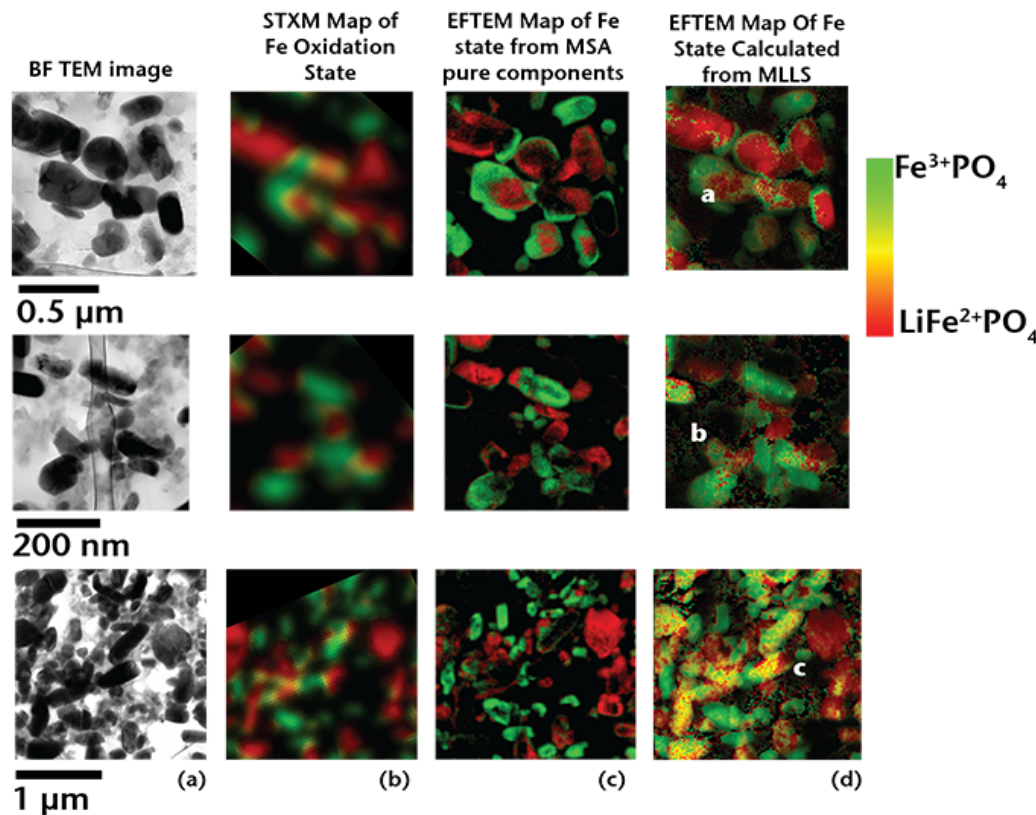
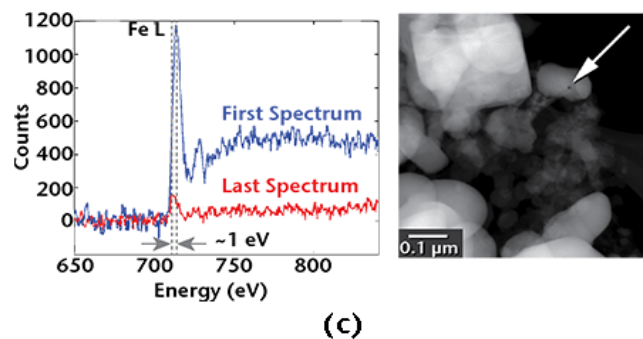
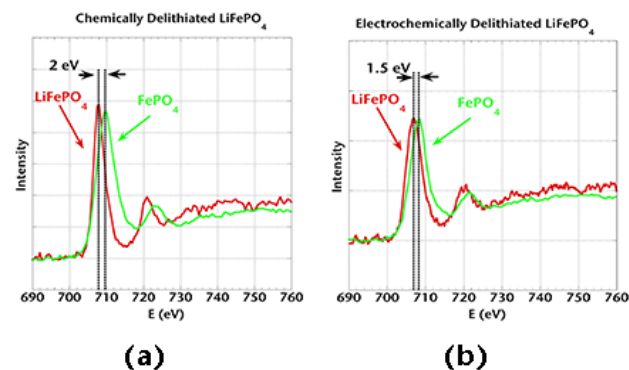




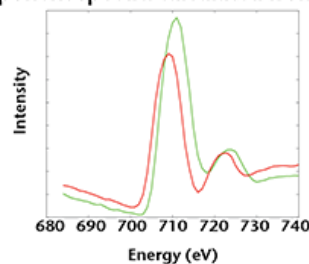
Phase analysis
Normalized to orange area



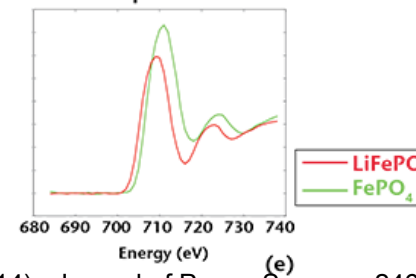
EELS studies



Component spectra calculated from MSA

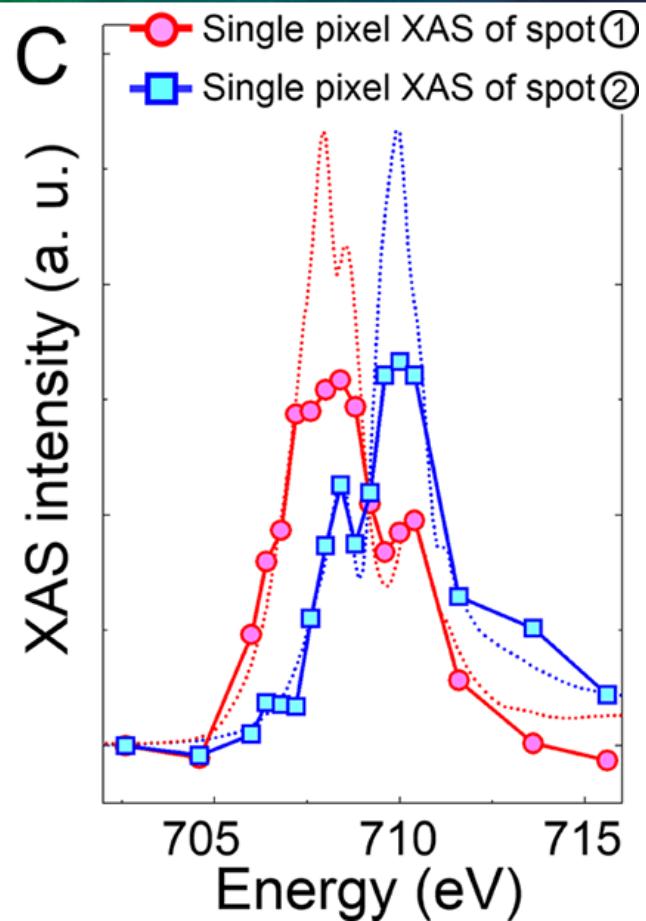
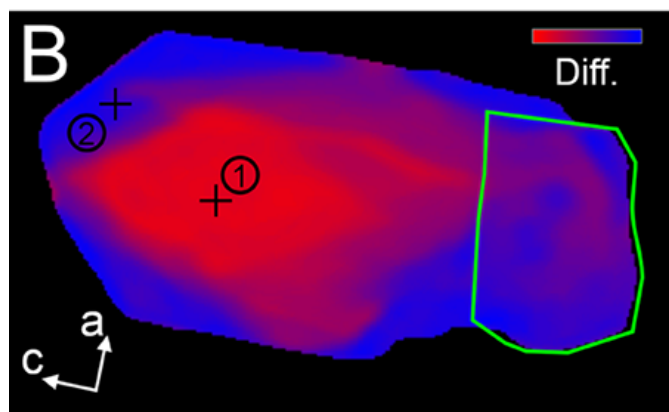
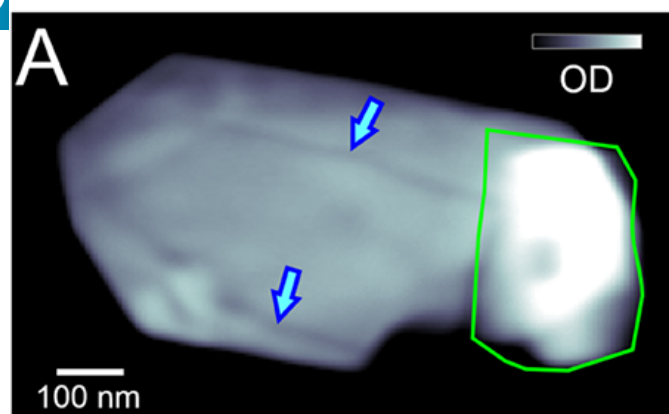


Reference Spectra used for MLLS fit



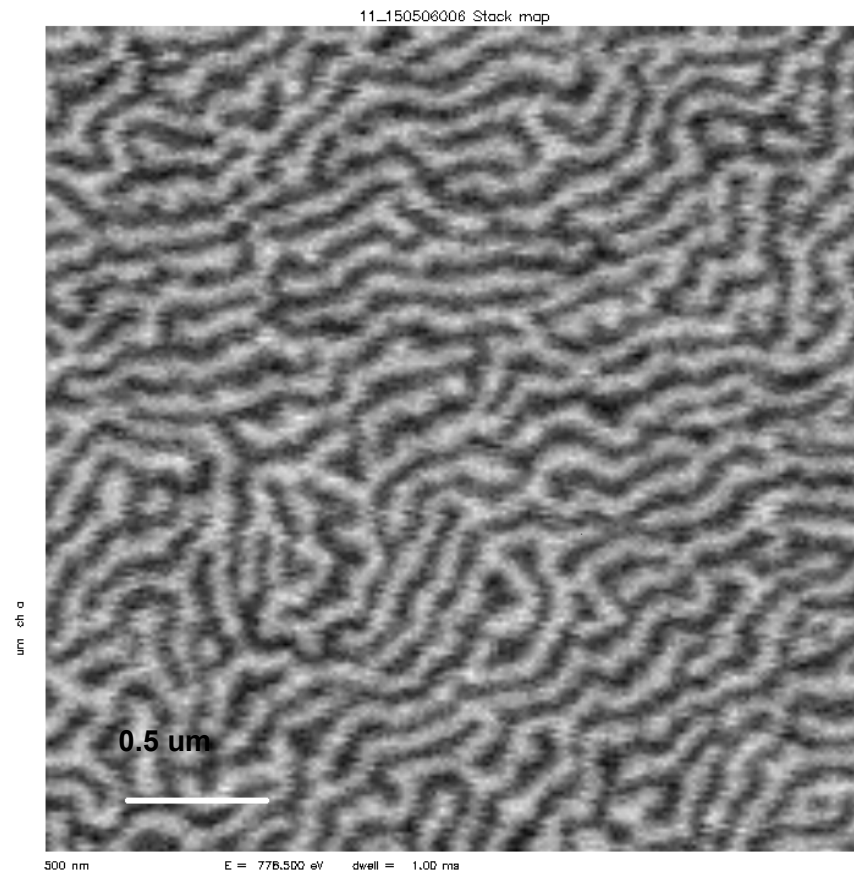
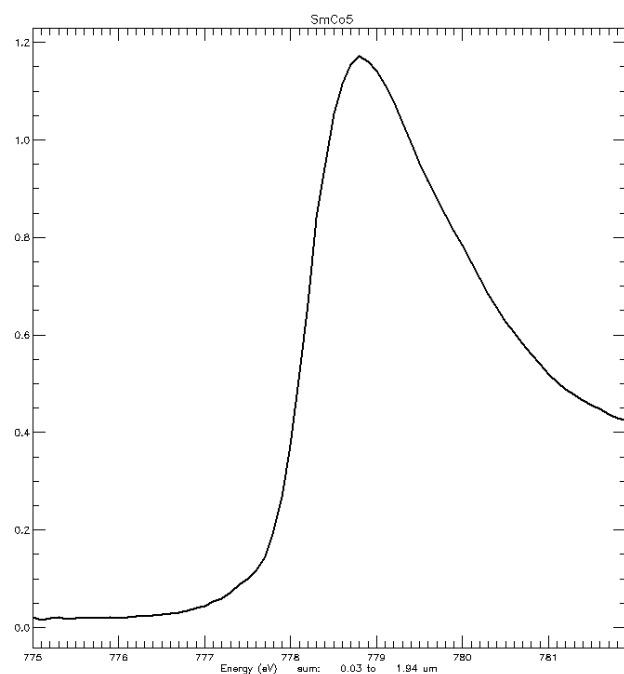
Sugar, J. D., El Gabaly, F., Chueh, W. C., Fenton, K. R., Tyliszczak, T., Kotula, P. G., & Bartelt, N. C. (2014).. Journal of Power Sources, 246, 512-521.

LiFePO₄ chemically partly delithated



Yu, Young-Sang, et al. "Dependence on crystal size of the nanoscale chemical phase distribution and fracture in Li_xFePO₄." Nano letters (2015).

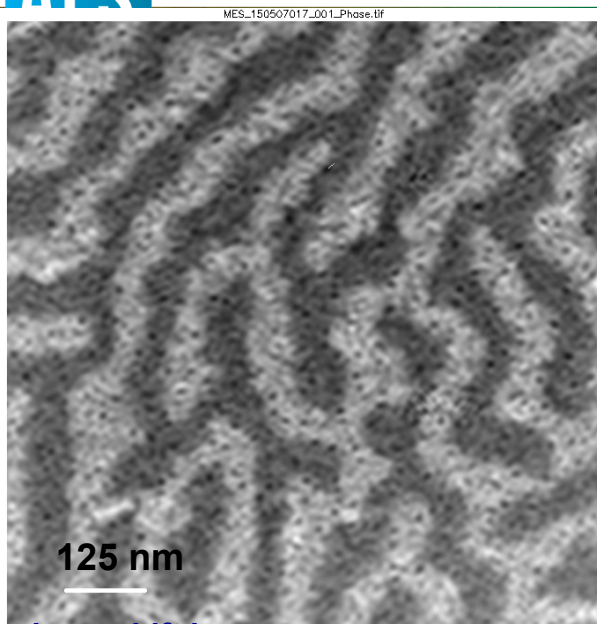
SmCo₅ sample – STXM XMCD



Work in progress

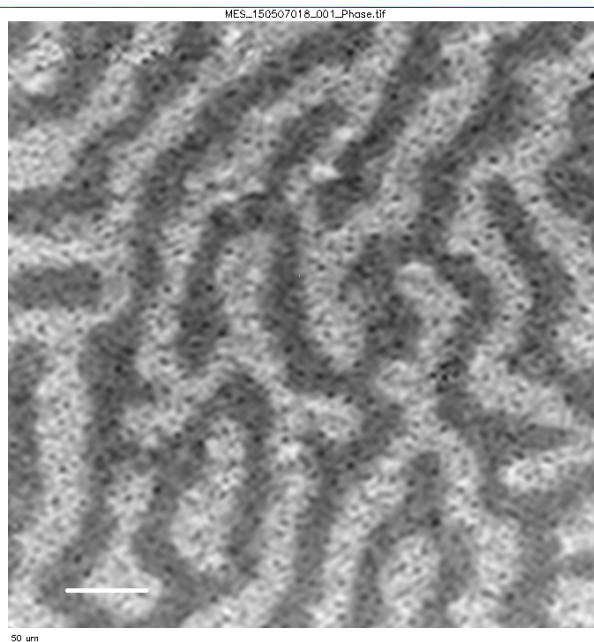
Xiaowen Shi, Hung Wei Shiu, Sujoy Roy, Peter Fisher, David Shapiro, Stephen Kevan, Youn-Sang Yu, Maryam Farmand

SmCo₅ at 778 eV – ptychography reconstruction

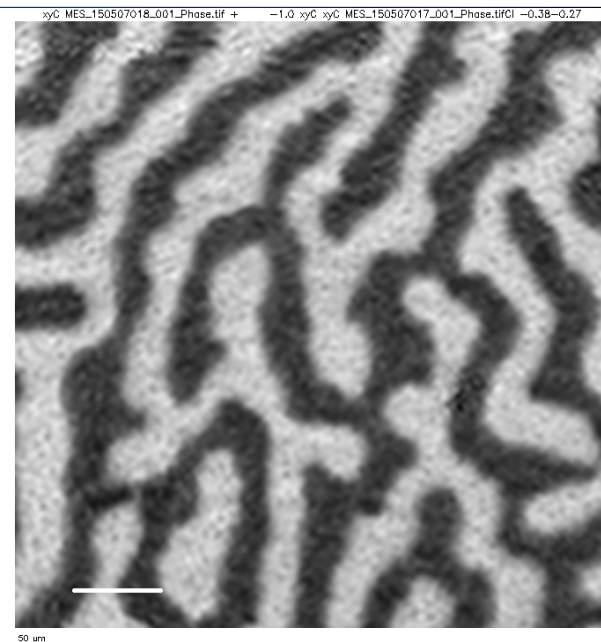


phase shift images

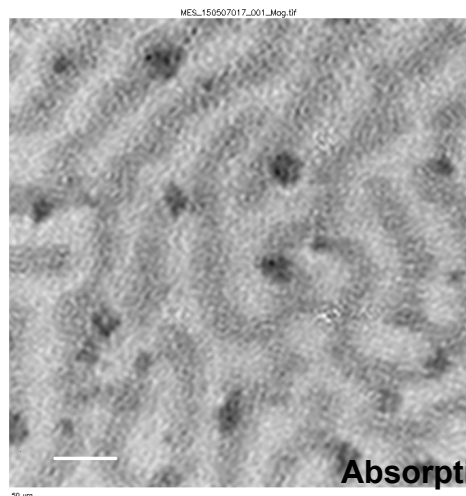
Polarization elliptical left



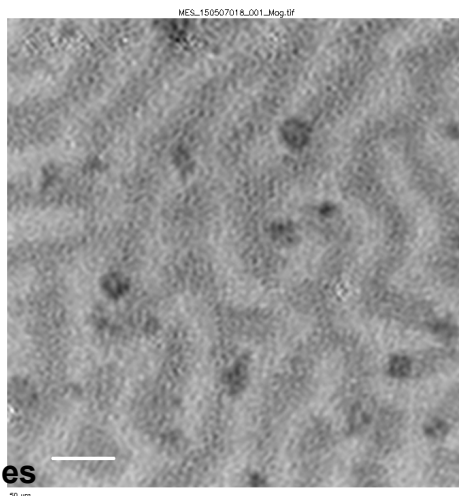
Polarization elliptical right



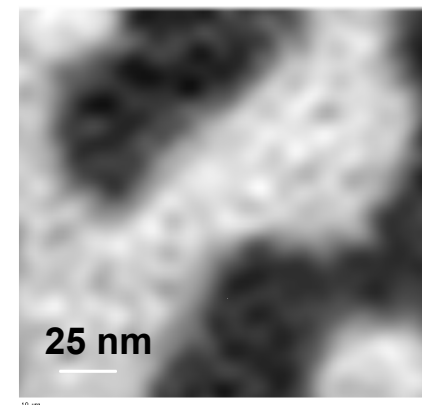
XMCD



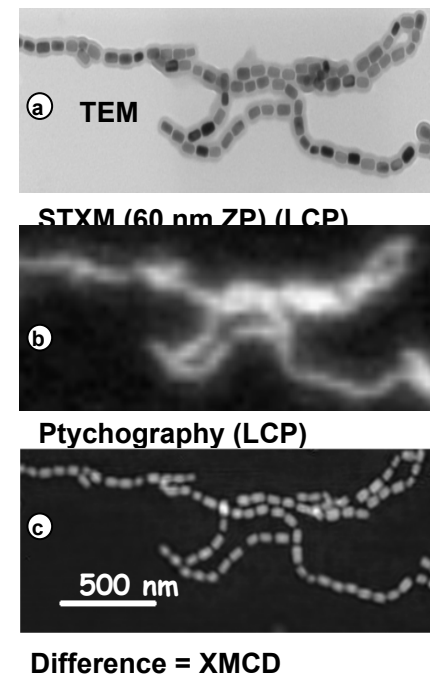
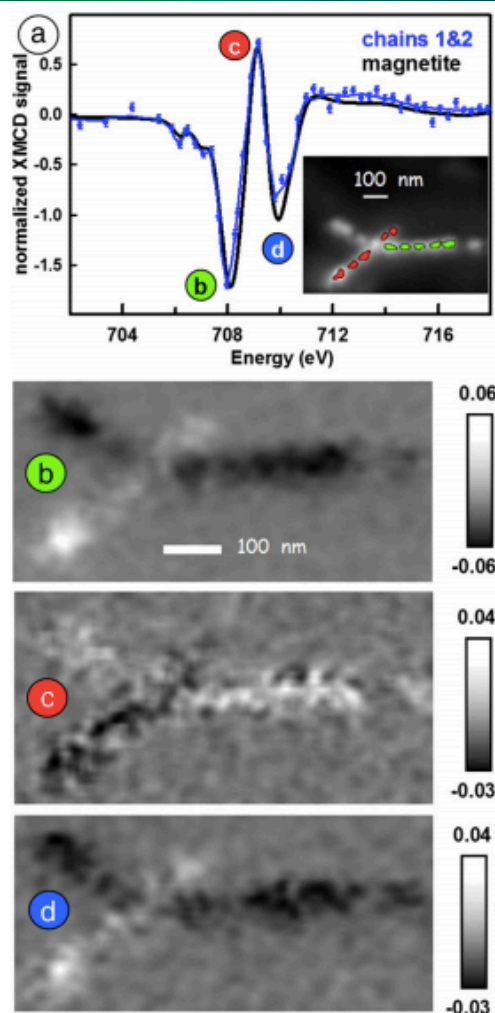
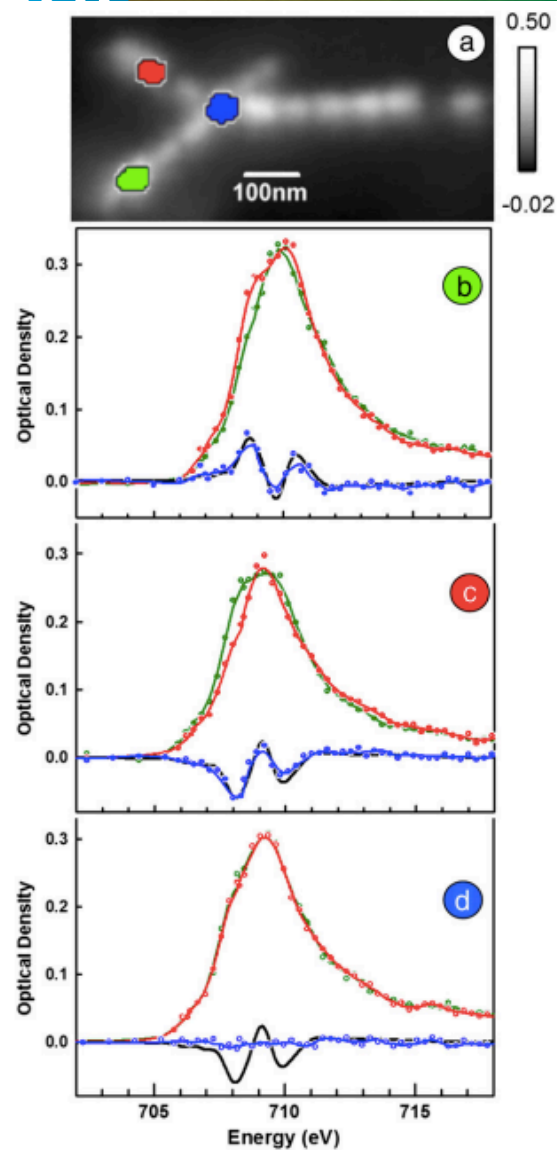
Absorption images



zoom



magnetism of magnetotactic bacterium *Candidatus Magnetovibrio blakemorei* strain MV-1



S.S. Kalirai et al. / Chemical Geology
300-301 (2012) 14–23

Intact MV-1 Cells

STXM Image of the Cell (708eV)



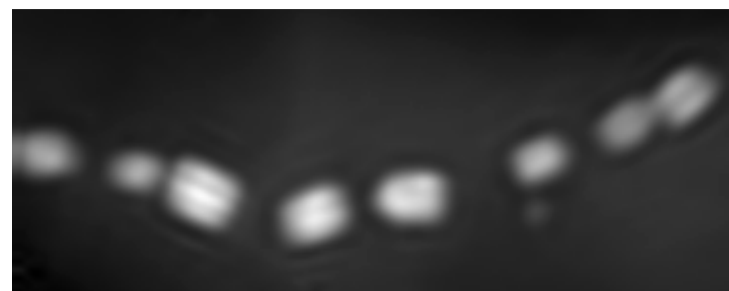
Left EP X-ray beam



XMCD (LCP-RCP)



Right EP X-ray beam



Ptychography - Work in progress
Xiaohui Zhu, T. Tyliszczak, H.-W. Shiu, D. Shapiro, D.A. Bazylnski, U. Lins⁵ and A.P. Hitchcock¹

Memristors – HP Lab

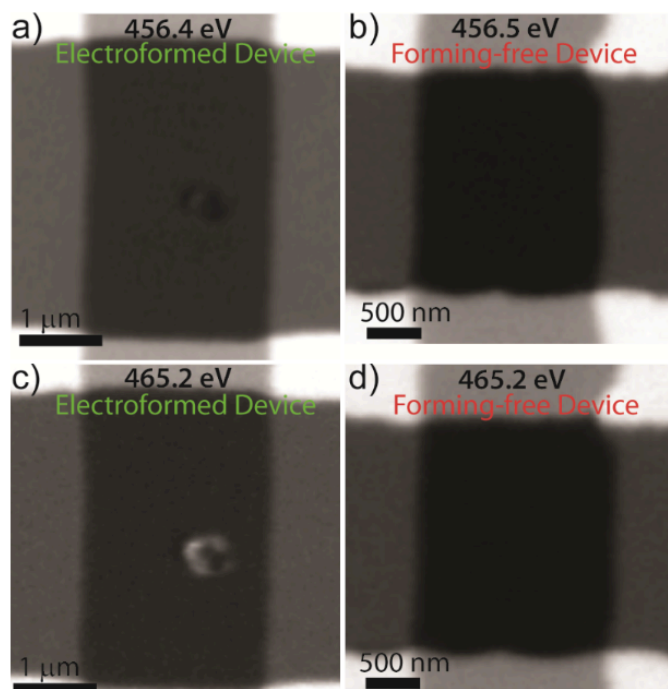


Figure 2: Comparison of scanning transmission X-ray micrographs for electroformed and forming-free devices. Contrast was derived from spatially-resolved X-ray absorption using incident monochromatic X-rays at the indicated energy which is before (456.4/456.5 eV) and within (465.2 eV) the main $Ti L_{2,3}$ edge. For the electroformed device, (a) and (c), a strong contrast was observed within the junction which reversed at the different X-ray energies, and

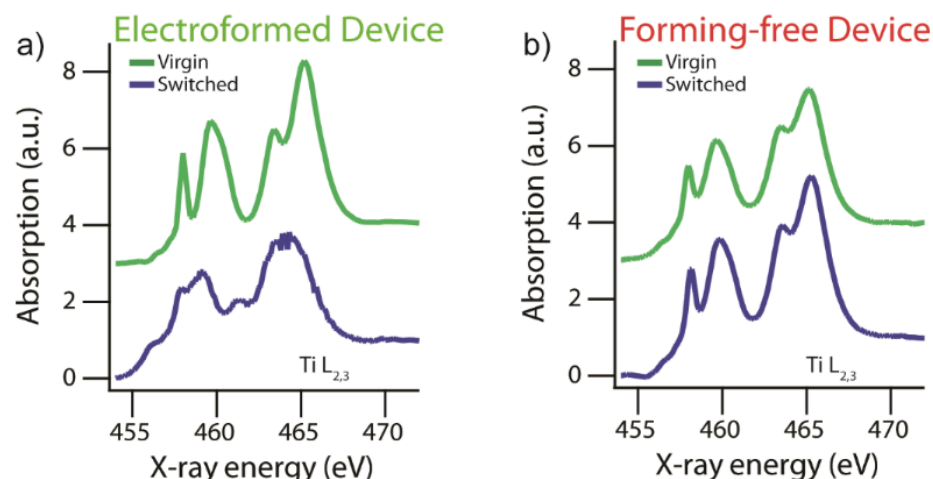


Figure 3: X-ray absorption spectroscopy within the junction region of an electroformed and forming-free device. The $Ti L_{2,3}$ absorption edge is shown, which is sensitive to chemical composition and structure state. (a) The "Virgin" NEXAFS spectrum (green curve) was derived from a neighboring, simultaneously grown device which was not electrically biased, while the "switched" spectrum (blue curve) came from within the material altered nanoscale region in the electroformed device of Figure 2 with a size of roughly $200\text{ nm} \times 200\text{ nm}$. (b) Both "Virgin" and "switched" spectra (green and blue curves, respectively) were derived from the junction region in the forming-free device of Figure 2, before and after the application of electrical bias, respectively.

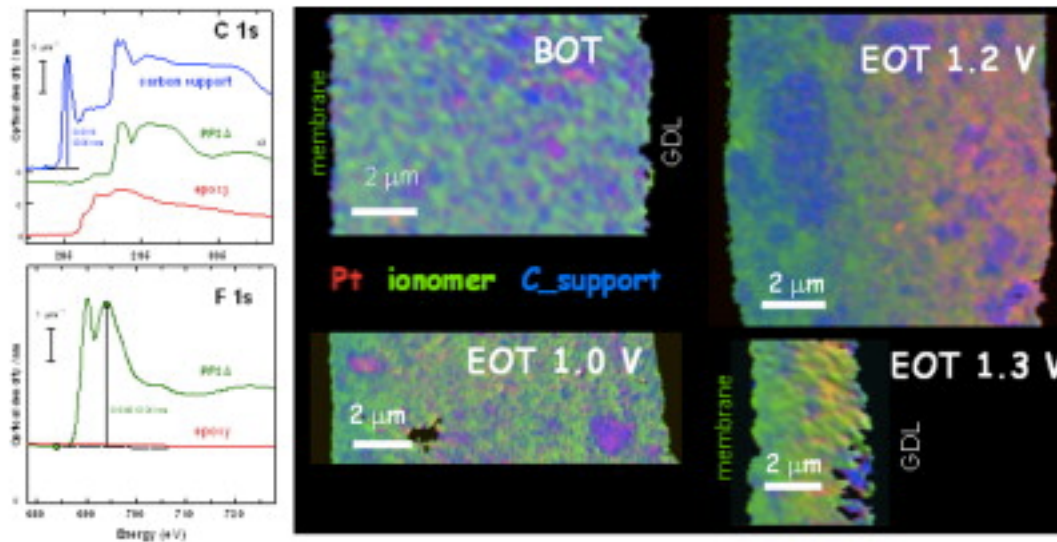
Strachan, J. P., Yang, J. J., Montoro, L. A., Ospina, C. A., Ramirez, A. J., Kilcoyne, A. L. D., ... & Williams, R. S. (2013). Characterization of electroforming-free titanium dioxide memristors. *Beilstein journal of nanotechnology*, 4(1), 467-473, 2013

Fuel cell membrane

Combination of open and proprietary research

Ballard Power Systems Inc, 9000 Glenlyon Parkway, Burnaby, BC V5J 5J9, Canada

Adam P. Hitchcock group, McMaster University, Hamilton, Canada



A.P. Hitchcock – AFCC (Automotive Fuel Cell Corporation)

Spectro-ptychography of a PEM-FC cathode

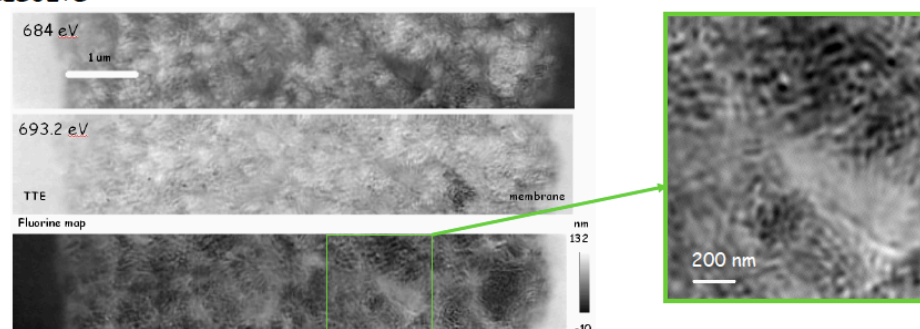
ALS STXM1102
17 Apr 2015

Xiaohui Zhu, Juan Wu, Adam Hitchcock (McMaster), H.-W. Shiu, David Shapiro, Tolek Tyliszczak (ALS); Viatcheslav Berejnov, Darija Susac, Juergen Stumper (AFCC)

GOALS: (1) explore spatial resolution improvements using ptychography
(2) determine if F 1s signal in cathode (ionomer) can be measured using ptychography

EXPERIMENTAL: AFCC sample A (from fall 2010) used. Microtomed sections were made in Aug 2011. These are embedded in TTE and mounted on formvar coated grid. Plate M150413-2.
Start 6:30 - did stxm stack for F 1s energy; beam lost 7:30 - 13:00 (!!); 13:00 - 15:00 ptycho set-up
15:00 - 17:00 - Ptycho Fluorine 1s stack map (693.2/684) over 8.5 μm x 1.5 μm (width of cathode) - 2.6 Gb

RESULTS:



CONCLUSION: F-mapping CAN be done with ptychography with not much more damage than regular STXM

PEM-FC-ptychography-stxm1102-apr2015.ppt 18-Apr-15

AFCC confidential

1



BASF – catalyst group

Collaboration with Bert Weckhuysen – Utrecht University

Acknowledgments

- David Shuh
- Hendrik Bluhm
- Mary Gilles
- Adam Hitchcock
- David Kilcoyne
- David Shapiro
- Hung-Wei Shiu

Conclusions

- Strong side of using soft X-rays – chemical information – spectroscopy on < 100 nm scale, especially good for C, N, O
- Relatively low radiation damage
- In-situ measurements
 - Many different environmental cells are used
 - In STXM – temperature 450 °C and 2 bar pressure
 - Working electrochemical cell
 - Working batteries (using fluorescence yield)
- Magnetization dynamics
- Ptychography – a new method allowing to use zone plates with much larger working distances. Much better spatial resolution (demonstrated 2 nm – potentially diffraction limited, C 4 nm, Mg 1 nm).